## **Freescale Semiconductor**

Data Sheet: Technical Data

Document Number: BSC9131 Rev. 0, 03/2014

# **BSC9131 QorIQ Qonverge Multicore Baseband Processor**

The following list provides an overview of the feature set:

- High-performance 32-bit e500 core built on Power Architecture® technology:
	- 36-bit physical addressing
	- Double-precision floating-point support
	- 32-Kbyte L1 instruction cache and 32-Kbyte L1 data cache
	- Enhanced hardware and software debug support
	- 800 MHz/1 GHz clock frequency
	- 256-Kbyte L2 cache with ECC; also configurable as SRAM and stashing memory
- One SC3850 core subsystem, which connects to the following:
	- 32 Kbyte 8-way level 1 data/instruction cache (L1 Dcache/ICache)
	- 512 Kbyte 8-way level 2 unified instruction/data cache (L2 cache/M2 memory)
	- Memory management unit (MMU)
	- Enhanced programmable interrupt controller (EPIC)
	- Debug and profiling unit (DPU)
	- Two 32-bit quad timers
- Multi Accelerator Platform Engine for Femto Base Station Baseband Processing (MAPLE-B2F)
	- Supports variable sizes in Fourier Transforms, Convolution, Filtering, Turbo, Viterbi, Chiprate
	- Consists of accelerators for UMTS chip rate processing, LTE UP/DL channel processing, Matrix Inversion operations, and CRC algorithms
- DDR3/DDR3L SDRAM memory controller supports 32-bit without ECC and 16-bit with ECC
- Integrated security engine (ULE CAAM)
	- Protocol support includes DES, AES, RNG, CRC, MDE, PKE, SHA, and MD5
- Secure boot capability
- Two enhanced three-speed Ethernet controllers (eTSECs)
	- $-10/100/1000$  Mbps support





- TCP/IP acceleration, quality of service, and classification capabilities
- IEEE Std 1588™ support
- eTSEC1 supports RGMII and RMII interfaces
- eTSEC2 supports an RGMII interface
- High-speed USB controller (USB 2.0)
	- Host and device support
	- Enhanced host controller interface (EHCI)
	- ULPI interface
- Enhanced secure digital (SD/MMC) host controller (eSDHC)
- Integrated Flash controller (IFC), supporting NAND, NOR, and general ASIC
- TDM with one TDM port
- Antenna interface controller (AIC), supporting three industry standard JESD/three custom parallel RF interfaces (two dual and one single port) and three MAXIM's MaxPHY serial interfaces
- Universal Subscriber Identity Module (USIM) interface – Facilitates communication to SIM cards or Eurochip pre-paid phone cards
- Four enhanced serial peripheral interfaces (eSPI)
- Programmable interrupt controller (PIC) compliant with OpenPIC standard
- One four-channel DMA controller
- Two  $I<sup>2</sup>C$  interfaces
- Two dual UART (DUART) interfaces
- Two pulse-width modulator (PWM) interfaces
- 96 general-purpose I/O signals
- Eight 32-bit timers
- Operating temperature (Ta T<sub>j</sub>) range:  $0-105^{\circ}$  C



© 2014 Freescale Semiconductor, Inc. All rights reserved.

# **Table of Contents**





This figure shows the major functional units.



**Figure 1. BSC9131 Block Diagram**

# <span id="page-2-0"></span>**1 Pin Assignments**

This section contains a top-level ball layout diagram followed by four detailed quadrant views and a pinout listing table.

## <span id="page-3-0"></span>**1.1 Ball Layout Diagrams**



**Figure 2. Ball Layout Diagram—Top-Level View**

#### [Figure 3](#page-4-0) shows detailed view A.



**DETAIL A**

<span id="page-4-0"></span>**Figure 3. Ball Layout Diagram—Detail A**

[Figure 4](#page-5-0) shows detailed view B.



**DETAIL B**

<span id="page-5-0"></span>**Figure 4. Ball Layout Diagram—Detail B**

[Figure 5](#page-6-0) shows detailed view C.



**DETAIL C**

<span id="page-6-0"></span>**Figure 5. Ball Layout Diagram—Detail C**

[Figure 6](#page-7-0) shows detailed view D.



<span id="page-7-0"></span>**Figure 6. Ball Layout Diagram—Detail D**

# <span id="page-8-0"></span>**1.2 Pinout Assignments**

This table provides the pinout listing.







































## **Table 1. BSC9131 Pinout Listing (continued)**
































































### **Pin Assignments**









### **Pin Assignments**



## **Table 1. BSC9131 Pinout Listing (continued)**

#### **Pin Assignments**

### **Table 1. BSC9131 Pinout Listing (continued)**



<sup>1</sup> This is a test signal for factory use only and must be pulled up (with 100 Ω –1 kΩ) to OVDD for normal operation.

 $2\degree$  This pin is a reset configuration pin. It has a weak internal pull-up P-FET which is enabled only when the processor is in the reset state. This pull-up is designed such that it can be overpowered by an external 4.7 kΩ pull-down resistor. However, if the signal is intended to be high after reset, and if there is any device on the net which might pull down the value of the net at reset, then a pull-up or active driver is needed.

- <sup>3</sup> This pin has a weak (~20 kΩ) internal pull-up P-FET that is always enabled.
- <sup>4</sup> This pin must NOT be pulled down during power-on reset.

<sup>5</sup> This pin is an open-drain signal.Recommend that a pull-up resistor (1 kΩ to 4.7 kΩ) be placed on this pin to the respective power supply.

- $6$  This pin should be pulled down to VSS with 10 kΩ.
- <sup>7</sup> This pin is used for fuse programming. Should be tied to VSS for normal operation (fuse read). See section Section 2.2, "Power [Sequencing,](#page-51-0)" for more details.
- 8 This pin may be connected to a temperature diode monitoring device such as the Analog Devices, ADT7461A™ or similar. If a temperature diode monitoring device will not be connected, these pins may be connected to test point or left as a no connect.
- <sup>9</sup> Pin should be pulled high or low depending on the JTAG topology selected. Refer to [Section 3.9, "JTAG Configuration Signals](#page-119-0)."

<sup>10</sup> This pin should be tied to GND/VSS when MAPLE is powered down, otherwise it should be tied to OVDD. Also with MAPLE module off, AIC (RF interfaces) and SPI2 modules are disabled.

- <sup>11</sup>. It has a weak internal pull-up P-FET which is enabled only when the processor is in the reset state. This pull-up is designed such that it can be overpowered by an external 4.7 kΩ pull-down resistor. However, if thesignal is intended to be high after reset, and if there is any device on the net which might pull down the value of the net at reset, then a pull-up or active driver is needed.
- <sup>12</sup> Do not connect. These pins should be left floating.

<sup>13</sup> These pins are connected to the same global power and ground (VDD, VDDC and GND) nets internally and may be connected as a differential pair to be used by the voltage regulators with remote sense function.

- <sup>14</sup> Recommend that a weak pull-up resistor (4.7 kΩ to 20 kΩ) be placed on this pin to the respective power supply.
- <sup>15</sup> Recommend that a weak pull-down resistor (4.7 kΩ) be placed on this pin.
- <sup>16</sup> Recommend that a weak pull-up resistor (10 to 100 kΩ) be placed on this pin to the respective power supply.
- <sup>17</sup> MDIC00 is grounded through an 36.5 Ω precision 1% resistor and MDIC01 is connected to GVDD through an 36.5 Ω precision 1% resistor. These pins are used for automatic calibration of the DDR3/DDR3L IOs.
- <sup>18</sup> Recommend that a weak pull-up resistor (4.7 kΩ) be placed on this pin.
- <sup>19</sup> When TEST\_SEL\_B is low the SPI2 I/F is disable.
- <sup>20</sup> Reset configuration default value is 1due to weak internal pull-up.
- <sup>21</sup> Reset configuration value doesn't have default.
- <sup>22</sup> Recommend that a weak pull-up resistor (4.7 kΩ to 20 kΩ) be placed on this pin to the respective power supply if it connected to an external device.

# **2 Electrical Characteristics**

This section provides the AC and DC electrical specifications. This device is currently targeted to these specifications. Some of these specifications are independent of the I/O cell, but are included for a more complete reference. These are not purely I/O buffer design specifications.

# **2.1 Overall DC Electrical Characteristics**

This section covers the ratings, conditions, and other characteristics.

## **2.1.1 Absolute Maximum Ratings**

<span id="page-47-0"></span>This table provides the absolute maximum ratings.







## **Table 2. Absolute Maximum Ratings<sup>1</sup> (continued)**

**Note:**

 $<sup>1</sup>$  Functional operating conditions are given in [Table 3.](#page-48-5) Absolute maximum ratings are stress ratings only, and functional</sup> operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.

- <sup>2</sup> AV<sub>DD</sub> is measured at the input to the filter and not at the pin of the device.
- <span id="page-48-0"></span><sup>3</sup> USIM pins are multiplexed with the pins of other interfaces. Check [Table 3](#page-48-5) for which power supply is used (BV<sub>DD</sub> or a CV<sub>DD</sub>) for each particular USIM pin.
- $4$  Caution: CV<sub>IN</sub> must not exceed CV<sub>DD</sub> by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
- <sup>5</sup> Caution: MV<sub>IN</sub> must not exceed GV<sub>DD</sub> by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
- <span id="page-48-1"></span> $6$  Caution: LV<sub>IN</sub> must not exceed LV<sub>DD</sub> by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
- <span id="page-48-2"></span> $7$  Caution: BV<sub>IN</sub> must not exceed BV<sub>DD</sub> by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
- <span id="page-48-3"></span><sup>8</sup> Caution: OV<sub>IN</sub> must not exceed OV<sub>DD</sub> by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
- <span id="page-48-4"></span><sup>9</sup> Caution: X[1-2]V<sub>IN</sub> must not exceed X[1-2]V<sub>DD</sub> by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
- <sup>10</sup> (C,X,B,G,L,O,R)V<sub>DD</sub> and MV<sub>REF</sub> may overshoot/undershoot to a voltage and for a maximum duration as shown in [Figure 7](#page-50-0).

## <span id="page-48-6"></span>**2.1.2 Recommended Operating Conditions**

This table provides the recommended operating conditions for this device. Note that the values in this table are the recommended and tested operating conditions. Proper device operation outside these conditions is not guaranteed.

#### **Table 3. Recommended Operating Conditions**

<span id="page-48-5"></span>



## **Table 3. Recommended Operating Conditions (continued)**



#### **Table 3. Recommended Operating Conditions (continued)**

**Note:**

<span id="page-50-1"></span><sup>1</sup> Caution: POV<sub>DD1</sub> must be supplied 1.5 V and the device must operate in the specified fuse programming temperature range only during secure boot fuse programming. For all other operating conditions, POV<sub>DD1</sub> must be tied to GND, subject to the power sequencing constraints shown in [Section 2.2, "Power Sequencing.](#page-51-0)"

- <span id="page-50-2"></span><sup>2</sup> USIM pins are multiplexed with the pins of other interfaces. Check [Table 3](#page-48-5) for which power supply is used (BV<sub>DD</sub> or a CV<sub>DD</sub>) for each particular USIM pin.
- <span id="page-50-3"></span><sup>3</sup> Unless otherwise stated in an interface's DC specifications, the maximum allowed input capacitance in this table is a general recommendation for signals.

This figure shows the undershoot and overshoot voltages at the interfaces.



### **Figure 7. Overshoot/Undershoot Voltage for BV<sub>DD</sub>/GV<sub>DD</sub>/LV<sub>DD</sub>/OV<sub>DD</sub>/X1V<sub>DD</sub>/X2V<sub>DD</sub>/RV<sub>DD</sub>**

<span id="page-50-0"></span>The core voltage must always be provided at nominal 1 V (see [Table 3](#page-48-5) for actual recommended core voltage). Voltage to the processor interface I/Os are provided through separate sets of supply pins and must be provided at the voltages shown in [Table 3.](#page-48-5) The input voltage threshold scales with respect to the associated I/O supply voltage.  $\text{OV}_{\text{DD}}$  and  $\text{LV}_{\text{DD}}$  based receivers are simple CMOS I/O circuits and satisfy appropriate LVCMOS type specifications. The DDR3 SDRAM interface uses a differential receiver referenced the externally supplied  $MV_{REF}$  signal (nominally set to  $GV_{DD}/2$ ). The DDR DQS receivers cannot be operated in single-ended fashion. The complement signal must be properly driven and cannot be grounded.

# **2.1.3 Output Driver Characteristics**

This table provides information on the characteristics of the output driver strengths. The values are preliminary estimates.



## **Table 4. Output Drive Capability**

**Note:**

<span id="page-51-1"></span><sup>1</sup> The drive strength of the DDR3 interface in half-strength mode is at T<sub>j</sub> = 125°C and at GV<sub>DD</sub> (min).

<span id="page-51-2"></span><sup>2</sup> USIM pins are multiplexed with the pins of other interfaces. Check [Table 3](#page-48-5) for which power supply is used (BV<sub>DD</sub> or a CV<sub>DD</sub>) for each particular USIM pin.

# <span id="page-51-0"></span>**2.2 Power Sequencing**

The device requires its power rails to be applied in a specific sequence in order to ensure proper device operation. These requirements are as follows for power up:

- 1. VDD, VDDC, AVDD (all PLL supplies)
- 2. LVDD, BVDD, CVDD, OVDD, X1VDD, X2VDD, GVDD
- 3. For secure boot fuse programming: After deassertion of HRESET\_B, drive  $POV_{DD1} = 1.5$  V after a required minimum delay per [Table 5.](#page-52-0) After fuse programming is completed, it is required to return  $POV_{DD1} = GND$  before the system is power cycled (HRESET\_B assertion) or powered down (V<sub>DDC</sub> ramp down) per the required timing specified in [Table 5.](#page-52-0) See [Section 3.11, "Security Fuse Processor,](#page-122-0)" for additional details.

## **WARNING**

Only 100,000 POR cycles are permitted per lifetime of a device. Only one secure boot fuse programming event is permitted per lifetime of a device.

No activity other than that required for secure boot fuse programming is permitted while POV<sub>DD1</sub> driven to any voltage above GND, including the reading of the fuse block. The reading of the fuse block may only occur while  $POV_{DD1} = GND$ .

POV<sub>DD2</sub> and POV<sub>DD3</sub> are always tied to GND.

This figure provides the  $POV<sub>DD1</sub>$  timing diagram.



**NOTE:** POVDD must be stable at 1.5 V prior to initiating fuse programming.

### **Figure 8. POV**<sub>DD1</sub> Timing Diagram

<span id="page-52-0"></span>This table provides information on the power-down and power-up sequence parameters for  $POV_{DD1}$ .

**Table 5. POV**<sub>DD1</sub> Timing <sup>5</sup>



**Note:**

1. Delay required from the deassertion of HRESET\_B to driving POV<sub>DD1</sub> ramp up. Delay measured from HRESET\_B deassertion at 90% OV<sub>DD</sub> to 10% POV<sub>DD1</sub> ramp up.

- 2. Delay required from fuse programming finished to POV<sub>DD1</sub> ramp down start. Fuse programming must complete while POV<sub>DD1</sub> is stable at 1.5 V. No activity other than that required for secure boot fuse programming is permitted while POV<sub>DD1</sub> driven to any voltage above GND, including the reading of the fuse block. The reading of the fuse block may only occur while POV<sub>DD1</sub> = GND. After fuse programming is completed, it is required to return POV<sub>DD1</sub> = GND.
- 3. Delay required from POV<sub>DD1</sub> ramp down complete to V<sub>DDC</sub> ramp down start. POV<sub>DD1</sub> must be grounded to minimum 10% POV $_{DD1}$  before V<sub>DDC</sub> is at 90% V<sub>DDC</sub>.
- 4. Delay required from POV<sub>DD1</sub> ramp down complete to HRESET\_B assertion. POV<sub>DD1</sub> must be grounded to minimum 10% POV<sub>DD1</sub> before HRESET\_B assertion reaches 90% OV<sub>DD</sub>.
- 5. Only one secure boot fuse programming event is permitted per lifetime of a device.

All supplies must be at their stable values within 50 ms.

Items on the same line have no ordering requirement with respect to one another. Items on separate lines must be ordered sequentially such that voltage rails on a previous step must reach 90% of their value before the voltage rails on the current step reach 10% of theirs.

In order to guarantee MCKE low during power-up, the above sequencing for GV<sub>DD</sub> is required. If there is no concern about any of the DDR signals being in an indeterminate state during power-up, the sequencing for  $GV<sub>DD</sub>$  is not required.

# **2.3 Power-Down Requirements**

The power-down cycle must complete such that power supply values are below 0.4 V before a new power-up cycle can be started.

# **2.4 RESET Initialization**

This section describes the AC electrical specifications for the RESET initialization timing requirements. [Table 6](#page-53-0) provides the RESET initialization AC timing specifications.

<span id="page-53-0"></span>

### **Table 6. RESET Initialization Timing Specifications**

#### **Note:**

1. There may be some extra current leakage when driving signals high during this time.

- 2. Reset assertion timing requirements for DDR3 DRAMs may differ.
- 3. TRST is an asynchronous level sensitive signal. For guidance on how this requirement can be met, refer to the JTAG signal termination guidelines in [Section 3.9.1, "Termination of Unused Signals.](#page-121-0)"
- 4. SYSCLK is the primary clock input.
- 5. Reset initialization should start only after all power supplies are stable.

This table provides the PLL lock times.

### **Table 7. PLL Lock Times**



# **2.5 Power-on Ramp Rate**

This section describes the AC electrical specifications for the power-on ramp rate requirements. Controlling the maximum power-on ramp rate is required to avoid falsely triggering the ESD circuitry. [Table 8](#page-53-1) provides the power supply ramp rate specifications.

### **Table 8. Power Supply Ramp Rate**

<span id="page-53-1"></span>

### **Table 8. Power Supply Ramp Rate (continued)**



**Note:**

1. Ramp rate is specified as a linear ramp from 10 to 90% of the nominal voltage of the specific voltage supply.

2. All MCKE signals must remain low during the power up sequence.

# **2.6 Power Characteristics**

This table shows the power dissipations of the  $V_{DDC}$  and  $V_{DD}$  supplies for various operating DSP and core complex bus clock (CCB\_clk) frequencies versus the core and DDR clock frequencies.

<b>Power</b> Mode	<b>PA Core</b> <b>Frequency</b> (MHz)	<b>DSP Core</b> <b>Frequency</b> (MHz)	<b>CCB</b> <b>Frequency</b> (MHz)	<b>PA DDR</b> <b>Frequency</b> (MHz)	(V)	$V_{DDC}$ Core   $V_{DD}$ MAPLE   (V)	Junction   Temp ( $^{\circ}$ C) $ $	$V_{DDC} + V_{DD}$ Power (W)	<b>Note</b>
Typical	1000	1000	500	800	1.0	1.0	65	3.4	1, 2
Thermal							105	5.0	1, 3, 5
<b>Maximum</b>								5.9	1, 4, 5
Typical	800	800	400	800	1.0	1.0	65	3.0	1, 2
Thermal							105	4.4	1, 3, 5
<b>Maximum</b>								5.2	1, 4, 5

**Table 9. Core Power Dissipation**

**Note:**

1. These values specify the power consumption at nominal voltage and apply to all valid processor bus frequencies and configurations. The values do not include power dissipation for I/O supplies.

- 2. Typical power is an average value measured while running a typical use case, using the nominal process and recommended core and platform (V<sub>DDC</sub>) and MAPLE (V<sub>DD</sub>) voltages at 65 °C junction temperature (see [Table 3](#page-48-5)).
- 3. Thermal power is the power measured while running a 70% (cores) and 50% (platform) utilization case, using the worst case process and recommended core and platform  $(V_{DDC})$  and MAPLE ( $V_{DD}$ ) voltages at maximum operating junction temperature (see [Table 3\)](#page-48-5).
- 4. Maximum power is the maximum power measured while running a maximum power pattern, using the worst case process and recommended core and platform ( $V_{DDC}$ ) and MAPLE ( $V_{DD}$ ) voltages at maximum operating junction temperature (see [Table 3\)](#page-48-5).
- 5. An estimated I/O power while running a typical use case, using the nominal process and recommended voltages of 1 W (see [Table 3\)](#page-48-5).

### **Table 10. I/O Power**



PS#	Primary pin name	<b>Pin</b> width	<b>Voltage domain</b>	Recommended value	Current max	<b>Typical</b> current (A)	Max (A)	<b>Note</b>
Analog	AVDD CORE		Core PLL supply			0.005	0.015	
	AVDD PLAT		Platform PLL supply	1.0V				
	AVDD DDR		DDR PLL supply					

**Table 10. I/O Power (continued)**

**Note:**

<sup>1</sup> For DDR typical, it is 40% DIMM utilization.

<sup>2</sup> For DDR max, it is 75% DIMM utilization.

 $3$  For I/O with different possible voltages, the currents listed above are for the higher voltage.

# **2.7 Input Clocks**

This section provides information about the system clock specifications, spread spectrum sources, real time clock specifications, eTSEC gigabit reference clock specifications, TDM clock specifications, and other input sources.

## **2.7.1 System Clock and DDR Clock Specifications**

This table provides the system clock (SYSCLK) and DDR clock (DDRCLK) 3.3 V DC specifications.

### **Table 11. SYSCLK/DDRCLK DC Electrical Characteristics**

At recommended operating conditions with  $OV<sub>DD</sub> = 3.3 V ± 165 mV$ 



#### **Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max OV<sub>IN</sub> values found in [Table 3.](#page-48-5)

2. The symbol  $V_{IN}$ , in this case, represents the  $OV_{IN}$  symbol referenced in [Table 3](#page-48-5).

This table provides the system clock (SYSCLK) and DDR clock (DDRCLK) AC timing specifications.

## **Table 12. SYSCLK/DDRCLK AC Timing Specifications**

#### At recommended operating conditions with  $OV<sub>DD</sub> = 3.3 V ± 165 mV$



### **Table 12. SYSCLK/DDRCLK AC Timing Specifications (continued)**

At recommended operating conditions with  $OV<sub>DD</sub> = 3.3 V ± 165 mV$ 



**Note:**

1. **Caution:** The relevant clock ratio settings must be chosen such that the resulting SYSCLK frequency do not exceed their respective maximum or minimum operating frequencies.

2. Measured at the rising edge and/or the falling edge at  $OV<sub>DD</sub>/2$ .

3. Slew rate as measured from  $\pm 0.3 \Delta V_{AC}$  at the center of peak to peak voltage at clock input.

4. Phase noise is calculated as FFT of TIE jitter.

# **2.7.2 DSP Clock (DSPCLKIN) Specifications**

This table provides the DSP clock (DSPCLKIN) 3.3 V DC specifications.

### **Table 13. DSPCLKIN DC Electrical Characteristics**

At recommended operating conditions with  $OV<sub>DD</sub> = 3.3 V ± 165 mV$ 



**Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max OV<sub>IN</sub> values found in [Table 3.](#page-48-5)

2. The symbol  $V_{IN}$ , in this case, represents the  $OV_{IN}$  symbol referenced in [Table 3](#page-48-5).

This table provides the DSP clock (DSPCLKIN) AC timing specifications.

### **Table 14. DSPCLKIN AC Timing Specifications**

At recommended operating conditions with  $OV<sub>DD</sub> = 3.3 V ± 165 mV$ 



### **Table 14. DSPCLKIN AC Timing Specifications (continued)**

At recommended operating conditions with  $OV<sub>DD</sub> = 3.3 V ± 165 mV$ 



**Note:**

- 1. **Caution:** The relevant clock **r**atio settings must be chosen such that the resulting DSPCLKIN frequency do not exceed their respective maximum or minimum operating frequencies.
- 2. Measured at the rising edge and/or the falling edge at  $OV<sub>DD</sub>/2$ .
- 3. Slew rate as measured from  $\pm 0.3 \Delta V_{AC}$  at the center of peak to peak voltage at clock input.
- 4. Phase noise is calculated as FFT of TIE jitter.

## **2.7.3 Spread Spectrum Sources**

Spread spectrum clock sources are an increasingly popular way to control electromagnetic interference emissions (EMI) by spreading the emitted noise to a wider spectrum and reducing the peak noise magnitude in order to meet industry and government requirements. These clock sources intentionally add long-term jitter in order to diffuse the EMI spectral content. The jitter specification given in this table considers short-term (cycle-to-cycle) jitter only and the clock generator's cycle-to-cycle output jitter should meet the input cycle-to-cycle jitter requirement. Frequency modulation and spread are separate concerns, and the device is compatible with spread spectrum sources if the recommendations listed in this table are observed.

### **Table 15. Spread Spectrum Clock Source Recommendations**

At recommended operating conditions. See [Table 3](#page-48-5).



**Note:**

1. SYSCLK frequencies resulting from frequency spreading, and the resulting core and VCO frequencies, must meet the minimum and maximum specifications given in [Table 95.](#page-114-0)

2. Maximum spread spectrum frequency may not result in exceeding any maximum operating frequency of the device

## **CAUTION**

The processor's minimum and maximum SYSCLK, core, and VCO frequencies must not be exceeded regardless of the type of clock source. Therefore, systems in which the processor is operated at its maximum rated e500 core frequency should avoid violating the stated limits by using down-spreading only.

## **2.7.4 Real Time Clock Specifications**

The RTC input is sampled by the platform clock (CCB clock). The output of the sampling latch is then used as an input to the counters of the PIC and the TimeBase unit of the e500. There is no jitter specification. The minimum pulse width of the RTC signal should be greater than 2x the period of the CCB clock. That is, minimum clock high time is  $2 \times t_{CCR}$ , and minimum clock low time is  $2 \times t_{\text{CCB}}$ . There is no minimum RTC frequency; RTC may be grounded if not needed.

## **2.7.5 eTSEC Gigabit Reference Clock Specifications**

[Table 16](#page-58-0) lists the eTSEC gigabit reference clock DC electrical characteristics.



<span id="page-58-0"></span>

**Note:**

1. The max  $V_{\text{IH}}$ , and min  $V_{\text{IL}}$  values can be found in [Table 3.](#page-48-5)

2. The symbol  $V_{IN}$ , in this case, represents the  $OV_{IN}$  symbol referenced in [Table 3](#page-48-5).

<span id="page-58-1"></span>[Table 17](#page-58-1) provides the eTSEC gigabit reference clocks (TSECn GTX CLK125) AC timing specifications.

### **Table 17. TSECn\_GTX\_CLK125 AC Timing Specifications**

At recommended operating conditions with  $LV_{DD} = 2.5 \pm 0.125$  mV



#### **Note:**

1. Rise and fall times for TSECn\_GTX\_CLK125 are measured from 0.5 and 2.0 V for LV<sub>DD</sub> = 2.5 V and from 0.6 .

2. TSECn\_GTX\_CLK125 is used to generate the GTX clock for the eTSEC transmitter with 2% degradation. The TSECn\_GTX\_CLK125 duty cycle can be loosened from 47%/53% as long as the PHY device can tolerate the duty cycle generated by the eTSEC GTX\_CLK. See [Section 2.11.1.2, "RMII and RGMII AC Timing Specifications,](#page-71-0)" for the duty cycle for 10Base-T and 100Base-T reference clock.

## **2.7.6 RF Parallel Interface Clock Specifications**

The following table lists the RF parallel interface clock DC electrical characteristics.

#### **Table 18. RF Parallel Reference Clock DC Electrical Characteristics**



**Note:**

1. The max  $V_{I}H$ , and min  $V_{I}L$  values can be found in [Table 3.](#page-48-5)

2. The symbol  $V_{IN}$ , in this case, represents the  $OV_{IN}$  symbol referenced in [Table 3](#page-48-5).

The following table lists the RF parallel interface clock AC electrical characteristics.

### **Table 19. RF Parallel Reference Clock AC Electrical Characteristics**

At recommended operating conditions with  $OV<sub>DD</sub> = 3.3 V ± 165 mV$ 



**Note:**

1. Slew rate as measured from  $\pm 0.3 \Delta V_{AC}$  at the center of peak to peak voltage at clock input.

## **2.7.7 RF Serial (MaxPHY) Interface Clock Specifications**

<span id="page-59-0"></span>[Table 20](#page-59-0) lists the RF serial (MaxPHY) interface clock DC electrical characteristics.

### **Table 20. RF Serial (MaxPHY) Reference Clock DC Electrical Characteristics**



#### **Note:**

1. The max  $V_{\text{IH}}$ , and min  $V_{\text{IL}}$  values can be found in [Table 3.](#page-48-5)

2. The symbol  $V_{IN}$ , in this case, represents the  $OV_{IN}$  symbol referenced in [Table 3](#page-48-5).

<span id="page-59-1"></span>[Table 21](#page-59-1) lists the RF serial (MaxPHY) interface clock AC electrical characteristics.

### **Table 21. RF Serial (MaxPHY) Reference Clock AC Electrical Characteristics**

At recommended operating conditions with  $OV<sub>DD</sub> = 3.3 V ± 165 mV$ 



**Note:**

1. Slew rate as measured from  $\pm 0.3 \Delta V_{AC}$  at the center of peak to peak voltage at clock input.

## **2.7.8 Other Input Clocks**

A description of the overall clocking of this device is available in the *BSC9131QorIQ Qonverge Multicore Baseband Processor Reference Manual* in the form of a clock subsystem block diagram. For information about the input clock requirements of other functional blocks such asEthernet Management, eSDHC, and IFC, see the specific interface section.

# **2.8 DDR3 and DDR3L SDRAM Controller**

This section describes the DC and AC electrical specifications for the DDR3 and DDR3L SDRAM controller interface. Note that the required GV<sub>DD</sub>(typ) voltage is 1.5 V and 1.35 V when interfacing to DDR3 or DDR3L SDRAM, respectively.

## **2.8.1 DDR3 and DDR3L SDRAM Interface DC Electrical Characteristics**

This table provides the recommended operating conditions for the DDR SDRAM controller when interfacing to DDR3 SDRAM.

### **Table 22. DDR3 SDRAM Interface DC Electrical Characteristics**

At recommended operating condition with  $GV<sub>DD</sub> = 1.5 V<sup>1</sup>$ 



**Note:**

1. GV<sub>DD</sub> is expected to be within 50 mV of the DRAM's voltage supply at all times. The DRAM's and memory controller's voltage supply may or may not be from the same source.

- 2. MVREFn is expected to be equal to  $0.5 \times GV_{DD}$  and to track GV<sub>DD</sub> DC variations as measured at the receiver. Peak-to-peak noise on MVREFn may not exceed  $\pm 1\%$  of the DC value.
- 3.  $V_{TT}$  is not applied directly to the device. It is the supply to which far end signal termination is made, and it is expected to be equal to MVREFn with a min value of MVREFn – 0.04 and a max value of MVREFn + 0.04. V<sub>TT</sub> should track variations in the DC level of MVREFn.
- 4. The voltage regulator for MVREFn must be able to supply up to 125  $\mu$ A current.
- 5. Input capacitance load for DQ, DQS, and DQS\_B are available in the IBIS models.
- 6. Output leakage is measured with all outputs disabled, 0  $V \leq V_{\text{OUT}} \leq GV_{\text{DD}}$ .

This table provides the recommended operating conditions for the DDR SDRAM controller when interfacing to DDR3L SDRAM.

## **Table 23. DDR3L SDRAM Interface DC Electrical Characteristics**

At recommended operating condition with GV<sub>DD</sub> = 1.35 V<sup>1</sup>



### **Table 23. DDR3L SDRAM Interface DC Electrical Characteristics (continued)**

At recommended operating condition with GV<sub>DD</sub> = 1.35 V<sup>1</sup>



#### **Note:**

- 1.  $GV<sub>DD</sub>$  is expected to be within 50 mV of the DRAM's voltage supply at all times. The DRAM's and memory controller's voltage supply may or may not be from the same source.
- 2. MVREFn is expected to be equal to  $0.5 \times GV_{DD}$  and to track GV<sub>DD</sub> DC variations as measured at the receiver.Peak-to-peak noise on MVREFn may not exceed the MVREFn DC level by more than  $\pm 1\%$  of GV<sub>DD</sub> (i.e.  $\pm 13.5$  mV).
- 3.  $V_{TT}$  is not applied directly to the device. It is the supply to which far end signal termination is made, and it is expected to be equal to MVREFn with a min value of MVREFn – 0.04 and a max value of MVREFn + 0.04. V<sub>TT</sub> should track variations in the DC level of MVREFn.
- 4. The voltage regulator for MVREFn must be able to supply up to125  $\mu$ A current.
- 5. Input capacitance load for DQ, DQS, and DQS\_B are available in the IBIS models.
- 6. IOH and IOL are measured at  $GV<sub>DD</sub> = 1.282$  V
- 7. See the IBIS model for the complete output IV curve characteristics.
- 8. Output leakage is measured with all outputs disabled, 0  $V \leq V_{\text{OUT}} \leq GV_{\text{DD}}$ .

This table provides the DDR controller interface capacitance for DDR3.

#### **Table 24. DDR3 SDRAM Capacitance**

At recommended operating conditions with GV<sub>DD</sub> of 1.5 V  $\pm$  5% for DDR3 or 1.35 V  $\pm$  5% for DDR3L.



This table provides the current draw characteristics for MVREF*n*.

#### **Table 25. Current Draw Characteristics for MVREFn**

For recommended operating conditions, se[eTable 3.](#page-48-5)



## **2.8.2 DDR3 and DDR3L SDRAM Interface AC Timing Specifications**

This section provides the AC timing specifications for the DDR SDRAM controller interface. The DDR controller supports DDR3 and DDR3L memories. Note that the required  $GV<sub>DD</sub>(typ)$  voltage is 1.5 V when interfacing to DDR3 SDRAM, and the required  $GV<sub>DD</sub>(typ)$  voltage is 1.35 V when interfacing to DDR3L SDRAM.

## **2.8.2.1 DDR3 and DDR3L SDRAM Interface Input AC Timing Specifications**

This table provides the input AC timing specifications for the DDR controller when interfacing to DDR3 SDRAM.

### **Table 26. DDR3 SDRAM Interface Input AC Timing Specifications**

For recommended operating conditions, see [Table 3.](#page-48-5)



### **Table 26. DDR3 SDRAM Interface Input AC Timing Specifications (continued)**

For recommended operating conditions, see Table 3.



This table provides the input AC timing specifications for the DDR controller when interfacing to DDR3L SDRAM.

#### **Table 27. DDR3L SDRAM Interface Input AC Timing Specifications**

For recommended operating conditions, see [Table 3.](#page-48-5)



This table provides the input AC timing specifications for the DDR controller when interfacing to DDR3/3L SDRAM.

### **Table 28. DDR3 and DDR3L SDRAM Interface Input AC Timing Specifications**

At recommended operating conditions with GV<sub>DD</sub> of 1.5 V  $\pm$  5% for DDR3 or 1.35 V  $\pm$  5% for DDR3L.



**Note:**

1.  $t_{CISKEY}$  represents the total amount of skew consumed by the controller between MDQS[n] and any corresponding bit that is captured with MDQS[n]. This should be subtracted from the total timing budget.

2. The amount of skew that can be tolerated from MDQS to a corresponding MDQ signal is called t<sub>DISKEW</sub>. This can be determined by the following equation:  $t_{DISKEW} = \pm (T \div 4 - abs(t_{CISKEW}))$  where T is the clock period and abs( $t_{CISKEW}$ ) is the absolute value of t<sub>CISKEW</sub>.

This figure shows the DDR3 and DDR3L SDRAM interface input timing diagram.



**Figure 9. DDR3 and DDR3L SDRAM Interface Input Timing Diagram**

## **2.8.2.2 DDR3 and DDR3L SDRAM Interface Output AC Timing Specifications**

<span id="page-63-0"></span>This table contains the output AC timing targets for the DDR3 and DDR3L SDRAM interface.

### **Table 29. DDR3 and DDR3L SDRAM Interface Output AC Timing Specifications**

At recommended operating conditions with GV<sub>DD</sub> of 1.5 V  $\pm$  5% for DDR3 or 1.35 V  $\pm$  5% for DDR3L.



### **Table 29. DDR3 and DDR3L SDRAM Interface Output AC Timing Specifications (continued)**

At recommended operating conditions with GV<sub>DD</sub> of 1.5 V  $\pm$  5% for DDR3 or 1.35 V  $\pm$  5% for DDR3L.



**Note:**

- 1. The symbols used for timing specifications follow the pattern of t<sub>(first two letters of functional block)(signal)(state) (reference)(state) for</sub> inputs and t(first two letters of functional block)(reference)(state)(signal)(state) for outputs. Output hold time can be read as DDR timing (DD) from the rising or falling edge of the reference clock (KH or KL) until the output went invalid (AX or DX). For example,  $t_{\text{DDKHAS}}$  symbolizes DDR timing (DD) for the time  $t_{\text{MCK}}$  memory clock reference (K) goes from the high (H) state until outputs (A) are setup (S) or output valid time. Also,  $t_{DDKLDX}$  symbolizes DDR timing (DD) for the time  $t_{MCK}$  memory clock reference (K) goes low (L) until data outputs (D) are invalid (X) or data output hold time.
- 2. All MCK/MCK\_B and MDQS/MDQS\_B referenced measurements are made from the crossing of the two signals.
- 3. ADDR/CMD includes all DDR SDRAM output signals except MCK/MCK\_B, MCS\_B, and MDQ/MECC/MDM/MDQS.
- 4. Note that t<sub>DDKHMH</sub> follows the symbol conventions described in note 1. For example, t<sub>DDKHMH</sub> describes the DDR timing (DD) from the rising edge of the MCK[n] clock (KH) until the MDQS signal is valid (MH). t<sub>DDKHMH</sub> can be modified through control of the MDQS override bits (called WR\_DATA\_DELAY) in the TIMING\_CFG\_2 register. This is typically set to the same delay as in DDR\_SDRAM\_CLK\_CNTL[CLK\_ADJUST]. The timing parameters listed in the table assume that these two parameters have been set to the same adjustment value. See the BSC9131 QorIQ Qonverge Multicore Baseband Processor Reference Manual for a description and explanation of the timing modifications enabled by use of these bits.
- 5. Determined by maximum possible skew between a data strobe (MDQS) and any corresponding bit of data (MDQ), ECC (MECC), or data mask (MDM). The data strobe should be centered inside of the data eye at the pins of the microprocessor.

## **NOTE**

For the ADDR/CMD setup and hold specifications in [Table 29](#page-63-0), it is assumed that the clock control register is set to adjust the memory clocks by ½ applied cycle.

This figure shows the DDR3 and DDR3L SDRAM interface output timing for the MCK to MDQS skew measurement  $(t_{\text{DDKHMH}})$ .



**Figure 10. t**<sub>DDKHMH</sub> Timing Diagram

This figure shows the DDR3 and DDR3L SDRAM output timing diagram.



**Figure 11. DDR3 and DDR3L Output Timing Diagram**

This figure provides the AC test load for the DDR3 and DDR3Lcontroller bus.



**Figure 12. DDR3 and DDR3L Controller Bus AC Test Load**

## **2.8.2.3 DDR3 and DDR3L SDRAM Differential Timing Specifications**

This section describes the DC and AC differential timing specifications for the DDR3 SDRAM controller interface. [Figure 13](#page-66-0) shows the differential timing specification.



**Figure 13. DDR3, and DDR3L SDRAM Differential Timing Specifications**

### **NOTE**

VTR specifies the true input signal (such as MCK or MDQS) and VCP is the complementary input signal (such as MCK\_B or MDQS\_B).

<span id="page-66-0"></span>This table provides the DDR3 differential specifications for the differential signals MDQS/MDQS\_B and MCK/MCK\_B.

### **Table 30. DDR3 SDRAM Differential Electrical Characteristics**



**Note:**

1. I/O drivers are calibrated before making measurements.

This table provides the DDR3 differential specifications for the differential signals MDQS/MDQS\_B and MCK/MCK\_B.

## **Table 31. DDR3L SDRAM Differential Electrical Characteristics**



**Note:**

1. I/O drivers are calibrated before making measurements.

# **2.9 eSPI**

This section describes the DC and AC electrical specifications for the SPI.

## **2.9.1 eSPI1 DC Electrical Characteristics**

This table provides the DC electrical characteristics for the eSPI1 on the device operating on a 3.3 V power supply.

### Table 32. eSPI1 DC Electrical Characteristics (CV<sub>DD</sub> = 3.3 V)

For recommended operating conditions, see [Table 3.](#page-48-5)



**Note:**

<sup>1</sup> The min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max OV<sub>IN</sub> values found in [Table 3.](#page-48-5)

<sup>2</sup> The symbol V<sub>IN</sub>, in this case, represents the OV<sub>IN</sub> symbol referenced in [Section 2.1.2, "Recommended Operating Conditions](#page-48-6)."

This table provides the DC electrical characteristics for the eSPI1, eSPI2, eSPI3, and eSPI4 on the device operating on a 1.8 V power supply.

### Table 33. eSPI DC Electrical Characteristics (CV<sub>DD</sub>, X2V<sub>DD</sub>, X1V<sub>DD</sub> = 1.8 V)

For recommended operating conditions, see [Table 3.](#page-48-5)



**Note:**

<sup>1</sup> The min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max OV<sub>IN</sub> values found in [Table 3.](#page-48-5)

<sup>2</sup> The symbol V<sub>IN</sub>, in this case, represents the OV<sub>IN</sub> symbol referenced in [Section 2.1.2, "Recommended Operating Conditions](#page-48-6)."

<span id="page-67-0"></span><sup>3</sup> eSPI1 is powered on CV<sub>DD</sub>, SPI2 is on X2V<sub>DD</sub>, SPI3 and SPI4 are on X1V<sub>DD</sub> (see [Table 3\)](#page-48-5).

## **2.9.2 eSPI1 AC Timing Specifications**

<span id="page-68-0"></span>This table provides the eSPI1 input and output AC timing specifications.

### **Table 34. eSPI1 AC Timing Specifications**

For recommended operating conditions, see [Table 3.](#page-48-5)



**Note:**

1. The symbols used for timing specifications follow the pattern of t<sub>(first two letters of functional block)(signal)(state) (reference)(state) for inputs</sub> and t<sub>(first two letters of functional block)(reference)(state)(signal)(state) for outputs. For example, t<sub>NIKHOV</sub> symbolizes the NMSI outputs</sub> internal timing (NI) for the time t<sub>SPI</sub> memory clock reference (K) goes from the high state (H) until outputs (O) are valid (V).

2. Output specifications are measured from the 50% level of the rising edge of CLKIN to the 50% level of the signal. Timings are measured at the pin.

<span id="page-68-1"></span>This figure provides the AC test load for eSPI1.



**Figure 14. eSPI1 AC Test Load**

This figure represents the AC timing from [Table 34](#page-68-0) in master mode (internal clock). Note that although the specifications are generally refer to the rising edge of the clock, [Figure 14](#page-68-1) also apply when the falling edge is the active edge. Also, note that the clock edge is selectable on eSPI1.



## **2.10 DUART**

This section describes the DC and AC electrical specifications for the DUART interfaces.

## **2.10.1 DUART DC Electrical Characteristics**

[Table 35](#page-69-0) and [Table 37](#page-70-0) provide the DC electrical characteristics for the two DUARTs on the device, which correspond to four UART interfaces. DUART1 is powered by  $\text{OV}_{\text{DD}}$ , while DUART2 is powered by the CV<sub>DD</sub>.

<span id="page-69-0"></span>This table provides the DC timing parameters for the DUART interface operating from a 3.3 V power supply.

### Table 35. DUART DC Electrical Characteristics (OV<sub>DD</sub>, CV<sub>DD</sub> = 3.3 V)

For recommended operating conditions, see [Table 3.](#page-48-5)



**Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max  $OV_N/CV_N$  values found in [Figure 3](#page-48-5).

2. Note that the symbol  $OV_{\text{IN}}/CV_{\text{IN}}$  represents the input voltage of the supply. It is referenced in [Figure 3](#page-48-5).

This table provides the DC timing parameters for the DUART interface operating from a 1.8 V power supply.

## Table 36. DUART DC Electrical Characteristics (CV<sub>DD</sub> = 1.8 V)

For recommended operating conditions, see [Table 3](#page-48-5).



**Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max CV<sub>IN</sub> values found in [Figure 3](#page-48-5).

2. Note that the symbol CV<sub>IN</sub> represents the input voltage of the supply. It is referenced in [Figure 3](#page-48-5).

# **2.10.2 DUART AC Electrical Specifications**

<span id="page-70-0"></span>This table provides the AC timing parameters for the DUART interface.

### **Table 37. DUART AC Timing Specifications**



**Note:**

- 1. CCB clock refers to the platform clock.
- 2. Actual attainable baud rate is limited by the latency of interrupt processing.
- 3. The middle of a start bit is detected as the  $8^{th}$  sampled 0 after the 1-to-0 transition of the start bit. Subsequent bit values are sampled each 16<sup>th</sup> sample.

# **2.11 Ethernet: Enhanced Three-Speed Ethernet (eTSEC)**

This section provides the AC and DC electrical characteristics for enhanced three-speed Ethernet10/100/1000 controller and MII management.

## **2.11.1 RMII/RGMII Interface Electrical Specifications**

This section provides AC and DC electrical characteristics of RMII/RGMII interface for eTSEC.

## **2.11.1.1 RMII and RGMII DC Electrical Characteristics**

<span id="page-71-1"></span>[Table 38](#page-71-1) presents the RGMII/RMII DC timing specifications.

### Table 38. RGMII/RMII DC Electrical Characteristics (LV<sub>DD</sub> = 3.3 V)

At recommended operating conditions with  $LV_{DD} = 3.3$  V



**Note:**

1. The min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max LV<sub>IN</sub> values found in [Table 3.](#page-48-5)

2. The symbol  $V_{IN}$ , in this case, represents the LV<sub>IN</sub> symbols referenced in [Table 2](#page-47-0) and [Table 3](#page-48-5).

<span id="page-71-2"></span>[Table 39](#page-71-2) shows the RGMII/RMII DC electrical characteristics when operating from a 2.5 V supply.

### Table 39. RGMII/RMII DC Electrical Characteristics (LV<sub>DD</sub> = 2.5 V)

At recommended operating conditions with  $LV_{DD} = 2.5$  V.



**Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max LV<sub>IN</sub> values found in [Table 3.](#page-48-5)

2. The symbol  $V_{IN}$ , in this case, represents the LV<sub>IN</sub> symbols referenced in [Table 3](#page-48-5).

## <span id="page-71-0"></span>**2.11.1.2 RMII and RGMII AC Timing Specifications**

<span id="page-71-3"></span>[Table 40](#page-71-3) presents the RMII transmit AC timing specifications.

### **Table 40. RMII Transmit AC Timing Specifications**

For recommended operating conditions, see [Table 3.](#page-48-5)


## **Table 40. RMII Transmit AC Timing Specifications (continued)**

For recommended operating conditions, see Table 3.



[Figure 16](#page-72-0) shows the RMII transmit AC timing diagram.



**Figure 16. RMII Transmit AC Timing Diagram**

<span id="page-72-1"></span><span id="page-72-0"></span>[Table 41](#page-72-1) lists the RMII receive AC timing specifications.

### **Table 41. RMII Receive AC Timing Specifications**

For recommended operating conditions, see [Table 3.](#page-48-0)



<span id="page-72-2"></span>[Figure 17](#page-72-2) provides the AC test load for eTSEC.



**Figure 17. eTSEC AC Test Load**

[Figure 18](#page-73-0) shows the RMII receive AC timing diagram.



**Figure 18. RMII Receive AC Timing Diagram**

<span id="page-73-1"></span><span id="page-73-0"></span>[Table 42](#page-73-1) presents the RGMII AC timing specifications.

### **Table 42. RGMII AC Timing Specifications**

For recommended operating conditions, see [Table 3.](#page-48-0)



**Note:**

1. In general, the clock reference symbol representation for this section is based on the symbols RGT to represent RGMII timing. For example, the subscript of  $t_{RGT}$  represents the TBI (T) receive (RX) clock. Note also that the notation for rise (R) and fall (F) times follows the clock symbol that is being represented. For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (RGT).

2. This implies that PC board design requires clocks to be routed such that an additional trace delay of greater than 1.5 ns is added to the associated clock signal. Many PHY vendors already incorporate the necessary delay inside their chip. If so, additional PCB delay is probably not needed.

3. For 10 and 100 Mbps,  $t_{\text{RGT}}$  scales to 400 ns  $\pm$  40 ns and 40 ns  $\pm$  4 ns, respectively.

4. Duty cycle may be stretched/shrunk during speed changes or while transitioning to a received packet's clock domains as long as the minimum duty cycle is not violated and stretching occurs for no more than three  $t_{\text{RGT}}$  of the lowest speed transitioned between.



[Figure 19](#page-74-1) shows the RGMII AC timing and multiplexing diagrams.

**Figure 19. RGMII AC Timing and Multiplexing Diagram**

# <span id="page-74-1"></span>**2.11.2 MII Management**

# **2.11.2.1 MII Management DC Electrical Characteristics**

The MDC and MDIO are defined to operate at a supply voltage of 3.3 V and 2.5 V. The DC electrical characteristics for MDIO and MDC are provided in [Table 43](#page-74-0) and [Table 44.](#page-75-0)

#### **Table 43. MII Management DC Electrical Characteristics**

<span id="page-74-0"></span>At recommended operating conditions with  $LV_{DD} = 3.3$  V.



## **Table 43. MII Management DC Electrical Characteristics (continued)**

At recommended operating conditions with  $LV_{DD} = 3.3$  V.



**Note:**

1. Note that the symbol  $V_{IN}$ , in this case, represents the LV<sub>IN</sub> symbol referenced in [Table 2](#page-47-0) and [Table 3.](#page-48-0)

### **Table 44. MII Management DC Electrical Characteristics**

<span id="page-75-0"></span>At recommended operating conditions with  $LV_{DD} = 2.5$  V.



#### **Note:**

1. EC1\_MDC and EC1\_MDIO operate on LV<sub>DD</sub>.

2. Note that the symbol  $V_{IN}$ , in this case, represents the LV<sub>IN</sub> and TV<sub>IN</sub> symbols referenced in [Table 3](#page-48-0).

# **2.11.2.2 MII Management AC Electrical Specifications**

This table provides the MII management AC timing specifications.

### **Table 45. MII Management AC Timing Specifications**



## **Table 45. MII Management AC Timing Specifications (continued)**



```
Note:
```
1. The symbols used for timing specifications follow the pattern of t<sub>(first two letters of functional block)(signal)(state)(reference)(state) for</sub> inputs and t<sub>(first two letters of functional block)(reference)(state)(signal)(state) for outputs. For example, t<sub>MDKHDX</sub> symbolizes management</sub> data timing (MD) for the time t<sub>MDC</sub> from clock reference (K) high (H) until data outputs (D) are invalid (X) or data hold time. Also, t<sub>MDDVKH</sub> symbolizes management data timing (MD) with respect to the time data input signals (D) reach the valid state (V) relative to the t<sub>MDC</sub> clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

- 2. This parameter is dependent on the platform clock frequency (MIIMCFG [MgmtClk] field determines the clock frequency of the MgmtClk Clock EC\_MDC).
- 3. This parameter is dependent on the platform clock frequency. The delay is equal to 16 platform clock periods ±3 ns. For example, with a platform clock of 333 MHz, the min/max delay is 48 ns ± 3 ns. Similarly, if the platform clock is 400 MHz, the min/max delay is 40 ns  $\pm$  3 ns.
- 4.  $t<sub>olb</sub>$  clk is the platform (CCB) clock.

This figure shows the MII management interface timing diagram.



**Figure 20. MII Management Interface Timing Diagram**

# **2.11.3 eTSEC IEEE Std 1588 Electrical Specifications**

# **2.11.3.1 eTSEC IEEE Std 1588 DC Specifications**

This table shows IEEE Std 1588 DC electrical characteristics when operating at  $LV_{DD} = 3.3$  V supply.

## Table 46. eTSEC IEEE 1588 DC Electrical Characteristics (LV<sub>DD</sub> = 3.3 V)

For recommended operating conditions with  $LV_{DD} = 3.3$  V.



## Table 46. eTSEC IEEE 1588 DC Electrical Characteristics (LV<sub>DD</sub> = 3.3 V) (continued)

For recommended operating conditions with  $LV_{DD} = 3.3$  V.



**Note:**

1. The min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max LV<sub>IN</sub> values found in [Table 3](#page-48-0).

2. The symbol  $V_{\text{IN}}$ , in this case, represents the LV<sub>IN</sub> symbols referenced in [Table 2](#page-47-0) and [Table 3](#page-48-0).

This table shows the IEEE 1588 DC electrical characteristics when operating at  $LV_{DD} = 2.5$  V supply.

## Table 47. eTSEC IEEE 1588 DC Electrical Characteristics (LV<sub>DD</sub> = 2.5 V)

For recommended operating conditions with  $LV_{DD} = 2.5 V$ 



**Note:**

1. The min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max LV<sub>IN</sub> values found in [Table 3.](#page-48-0)

2. The symbol  $V_{\text{IN}}$ , in this case, represents the LV<sub>IN</sub> symbols referenced in [Table 2](#page-47-0) and [Table 3](#page-48-0).

# **2.11.3.2 eTSEC IEEE Std 1588 AC Specifications**

This table provides the IEEE Std 1588 AC timing specifications.

## **Table 48. eTSEC IEEE 1588 AC Timing Specifications**

For recommended operating conditions, see [Table 3](#page-48-0)



### **Table 48. eTSEC IEEE 1588 AC Timing Specifications (continued)**

For recommended operating conditions, see Table 3



#### **Note:**

1.T<sub>RX\_CLK</sub> is the max clock period of eTSEC receiving clock selected by TMR\_CTRL[CKSEL]. See the BSC9131 QorIQ Qonverge Multicore Baseband Processor Reference Manual for a description of TMR\_CTRL registers.

2. It needs to be at least two times the clock period of the clock selected by TMR\_CTRL[CKSEL]. See the BSC9131 QorIQ Qonverge Multicore Baseband Processor Reference Manualfor a description of TMR\_CTRL registers.

3. The maximum value of  $t_{T1588CLK}$  is not only defined by the value of  $T_{RX\_CLK}$ , but also defined by the recovered clock. For example, for 10/100/1000 Mbps modes, the maximum value of  $t_{T1588CLK}$  is 2800, 280, and 56 ns respectively.

[Figure 21](#page-78-0) shows the data and command output AC timing diagram.



<sup>1</sup> eTSEC IEEE 1588 Output AC timing: The output delay is counted starting at the rising edge if  $t_{T1588CLKOUT}$  is non-inverting. Otherwise, it is counted starting at the falling edge.

#### **Figure 21. eTSEC IEEE 1588 Output AC Timing**

<span id="page-78-0"></span>This figure shows the data and command input AC timing diagram.



**Figure 22. eTSEC IEEE 1588 Input AC Timing**

# **2.12 USB**

This section provides the AC and DC electrical specifications for the USB interface.

# **2.12.1 USB DC Electrical Characteristics**

This table provides the DC electrical characteristics for the ULPI interface when operating at 3.3 V.

### Table 49. USB DC Electrical Characteristics (CV<sub>DD</sub>/LV<sub>DD</sub>/X2V<sub>DD</sub> = 3.3 V)

For recommended operating conditions, see [Table 3.](#page-48-0)



#### **Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max CV<sub>IN</sub>/LV<sub>IN</sub>/X2V<sub>IN</sub> values found in [Table 3.](#page-48-0) 2. Note that the symbol CV<sub>IN</sub>, LV<sub>IN</sub>, and X2V<sub>IN</sub> represent the input voltage of the power supplies. See [Table 3](#page-48-0).

[Table 51](#page-79-0) provides the DC electrical characteristics for the ULPI interface when operating at 2.5 V.

## Table 50. USB DC Electrical Characteristics (LV<sub>DD</sub> = 2.5 V)

For recommended operating conditions, see [Table 3.](#page-48-0)



#### **Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max LV<sub>IN</sub> values found in [Table 3](#page-48-0).

2. Note that the symbol  $LV_{\text{IN}}$  represents the input voltage of the supply. It is referenced in [Table 3.](#page-48-0)

<span id="page-79-0"></span>This table provides the DC electrical characteristics for the ULPI interface when operating at 1.8 V.

## Table 51. USB DC Electrical Characteristics (CV<sub>DD</sub>/X2V<sub>DD</sub> = 1.8 V)

For recommended operating conditions, see [Table 3.](#page-48-0)



## Table 51. USB DC Electrical Characteristics (CV<sub>DD</sub>/X2V<sub>DD</sub> = 1.8 V) (continued)

For recommended operating conditions, see Table 3.

#### **Note:**

- 1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max CV<sub>IN</sub>/X2V<sub>IN</sub> values found in [Table 3](#page-48-0).
- 2. Note that the symbol  $CV_{IN}/X2V_{IN}$  represents the input voltage of the supply. See [Table 3.](#page-48-0)

# **2.12.2 USB AC Electrical Specifications**

This table describes the general timing parameters of the USB interface of the device.

### **Table 52. USB General Timing Parameters (ULPI Mode)**

For recommended operating conditions, see [Table 3.](#page-48-0)



**Note:**

1. The symbols for timing specifications follow the pattern of  $t_{(First two letters of functional block)(signal)(state)(reference)(state)}$  for inputs and t<sub>(First two letters of functional block)(reference)(state)(signal)(state) for outputs. For example, t<sub>USIXKH</sub> symbolizes USB timing (US) for</sub> the input (I) to go invalid (X) with respect to the time the USB clock reference (K) goes high (H). Also, t<sub>USKHOX</sub> symbolizes USB timing (US) for the USB clock reference (K) to go high (H) with respect to the output (O) going invalid (X) or output hold time.

2. All timings are in reference to USB clock.

- 3. All signals are measured from BV<sub>DD</sub>/2 of the rising edge of the USB clock to 0.4  $\times$  OV<sub>DD</sub> of the signal in question for 3.3 V signaling levels.
- 4. Input timings are measured at the pin.
- 5. For active/float timing measurements, the high impedance or off state is defined to be when the total current delivered through the component pin is less than or equal to that of the leakage current specification.

<span id="page-80-0"></span>[Figure 23](#page-80-0) and [Figure 24](#page-81-0) provide the USB AC test load and signals, respectively.



**Figure 23. USB AC Test Load**



<span id="page-81-0"></span>This table provides the USB clock input (USB\_CLK\_IN) AC timing specifications.

**Table 53. USB\_CLK\_IN AC Timing Specifications**

<b>Parameter/Condition</b>	<b>Conditions</b>	Symbol	Min	<b>Typ</b>	Max	Unit
Frequency range	Steady state	<sup>I</sup> USB CLK IN	59.97	60	60.03	<b>MHz</b>
Clock frequency tolerance		<sup>I</sup> CLK TOL	$-0.05$	0	0.05	$\%$
Reference clock duty cycle	Measured at 1.6 V	<sup>I</sup> CLK DUTY	40	50	60	$\%$
Total input jitter/time interval error	Peak-to-peak value measured with a second order high-pass filter of 500 kHz bandwidth	<sup>t</sup> CLK_PJ			200	ps

# **2.13 Integrated Flash Controller (IFC)**

This section describes the DC and AC electrical specifications for the integrated flash controller.

# **2.13.1 IFC DC Electrical Characteristics**

This table provides the DC electrical characteristics for the integrated flash controller when operating at  $BV_{DD} = 3.3$  V.

## **Table 54. Integrated Flash Controller DC Electrical Characteristics (3.3 V)**

For recommended operating conditions, see [Table 3](#page-48-0)



## **Table 54. Integrated Flash Controller DC Electrical Characteristics (3.3 V) (continued)**

For recommended operating conditions, see Table 3



**Note:**

1. The min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max BV<sub>IN</sub> values found in [Table 3.](#page-48-0)

2. The symbol  $V_{IN}$ , in this case, represents the BV<sub>IN</sub> symbol referenced in Section 2.1.2, "Recommended Operating [Conditions](#page-48-1)."

This table provides the DC electrical characteristics for the integrated flash controller when operating at  $BV_{DD} = 2.5$  V.

### **Table 55. Integrated Flash Controller DC Electrical Characteristics (2.5 V)**

For recommended operating conditions, see [Table 3](#page-48-0)



**Note:**

1. The min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max BV<sub>IN</sub> values found in [Table 3](#page-48-0).

2. The symbol  $V_{\text{IN}}$ , in this case, represents the BV<sub>IN</sub> symbol referenced in [Section 2.1.2, "Recommended Operating Conditions](#page-48-1)."

This table provides the DC electrical characteristics for the integrated flash controller when operating at  $BV_{DD} = 1.8$  V.

**Table 56. Integrated Flash Controller DC Electrical Characteristics (1.8 V)**

For recommended operating conditions, see [Table 3](#page-48-0)



**Note:**

1. The min V<sub>IL</sub> and max V<sub>IH</sub> values are based on the respective min and max BV<sub>IN</sub> values found in [Table 3](#page-48-0).

2. The symbol  $V_{IN}$ , in this case, represents the BV<sub>IN</sub> symbol referenced in [Section 2.1.2, "Recommended Operating Conditions](#page-48-1)."

# **2.13.2 IFC AC Timing Specifications**

This section describes the AC timing specifications for the integrated flash controller.

# **2.13.2.1 Test Condition**

This figure provides the AC test load for the integrated flash controller.



**Figure 25. Integrated Flash Controller AC Test Load**

# **2.13.2.2 IFC AC Timing Specifications**

All output signal timings are relative to the falling edge of any IFC\_CLK. The external circuit must use the rising edge of the IFC\_CLKs to latch the data.

All input timings are relative to the rising edge of IFC CLKs.

This table describes the timing specifications of the integrated flash controller interface.

#### Table 57. IFC Timing Specifications (BV<sub>DD</sub> = 3.3 V, 2.5 V, and 1.8 V)

For recommended operating conditions, see [Table 3](#page-48-0)



**Note:**

1. All signals are measured from  $BV_{DD}/2$  of rising/falling edge of IFC\_CLK to  $BV_{DD}/2$  of the signal in question.

- 2. Skew measured between different IFC\_CLK signals at  $BV<sub>DD</sub>/2$ .
- 3. For purposes of active/float timing measurements, the high impedance or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
- 4. t<sub>IBONOT</sub> is a measurement of the maximum time between the negation of ALE and any change in AD when  $FTIMO_CSn[TEAHC] = 0.$
- 5. Here the negative sign means output transit happens earlier than the falling edge of IFC\_CLK.
- 6. Here a convention has been followed in which the more negative/less-positive the number, the smaller the number would be. For example –2 is smaller then –1 and –1 is smaller then 0. So if the min value of this parameter is shown as –2 ns than the for any part parameter's measure will never go to –3ns though it can go to –1 ns.

This figure shows the AC timing diagram.



<span id="page-84-0"></span>[Figure 26](#page-84-0) applies to all the controllers that IFC supports.

For input signals, the AC timing data is used directly for all controllers. For output signals, each type of controller provides its own unique method to control the signal timing. The final signal delay value for output signals is the programmed delay plus the AC timing delay.

This figure shows how the AC timing diagram applies to GPCM. The same principle also applies to other controllers of IFC.



1 t<sub>aco</sub>, t<sub>rad</sub>, t<sub>eahc</sub>, t<sub>eadc</sub>, t<sub>acse</sub>, t<sub>cs</sub>, t<sub>ch</sub>, t<sub>wp</sub> are programmable. See the BSC9131 QorIQ Qonverge Multicore Baseband Processor Reference Manual.

### **Figure 27. GPCM Output Timing Diagram**

# **2.14 Enhanced Secure Digital Host Controller (eSDHC)**

This section describes the DC and AC electrical specifications for the eSDHC interface.

# **2.14.1 eSDHC DC Electrical Characteristics**

This table provides the DC electrical characteristics for the eSDHC interface.

### **Table 58. eSDHC Interface DC Electrical Characteristics**





<sup>&</sup>lt;sup>2</sup> For output signals, each type of controller provides its own unique method to control the signal timing. The final signal delay value for output signals is the programmed delay plus the AC timing delay.

### **Table 58. eSDHC Interface DC Electrical Characteristics (continued)**

At recommended operating conditions with  $BV<sub>DD</sub> = 3.3 V$  or 1.8 V.



#### **Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max BV<sub>IN</sub> values found in [Figure 3](#page-48-0).

2. Open drain mode for MMC cards only.

# **2.14.2 eSDHC AC Timing Specifications**

This table provides the eSDHC AC timing specifications as defined in [Figure 29](#page-87-0).

### **Table 59. eSDHC AC Timing Specifications**

At recommended operating conditions with  $BV_{DD} = 3.3$  or 1.8 V



#### **Note:**

1. The symbols used for timing specifications herein follow the pattern of t<sub>(first three letters of functional block)(signal)(state)</sub> (reference)(state) for inputs and t<sub>(first three letters of functional block)(reference)(state)(signal)(state) for outputs. For example, t<sub>FHSKHOV</sub></sub> symbolizes eSDHC high speed mode device timing (SHS) clock reference (K) going to the high (H) state, with respect to the output (O) reaching the invalid state (X) or output hold time. Note that, in general, the clock reference symbol representation is based on five letters representing the clock of a particular functional. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

- 2. In full speed mode, clock frequency value can be 0–25 MHz for a SD/SDIO card and 0–20 MHz for a MMC card. In high speed mode, clock frequency value can be 0–50 MHz for a SD/SDIO card and 0–52 MHz for a MMC card.
- 3. To satisfy setup timing, one way board routing delay between Host and Card, on SD\_CLK, SD\_CMD and SD\_DATx should not exceed 1 ns for any high speed MMC card. For any high speed or default speed mode SD card, the one way board routing delay between Host and Card, on SD\_CLK, SD\_CMD and SD\_DATx should not exceed 1.5 ns.

4. CCARD ≤10 pF, (1 card), and CL = CBUS + CHOST + CCARD  $\leq$  40 pF

This figure provides the eSDHC clock input timing diagram.



**Figure 28. eSDHC Clock Input Timing Diagram**

This figure provides the data and command input/output timing diagram.



 $VM = Midpoint Voltage (BV<sub>DD</sub>/2)$ 

**Figure 29. eSDHC Data and Command Input/Output Timing Diagram Referenced to Clock**

# <span id="page-87-0"></span>**2.15 Programmable Interrupt Controller (PIC) Specifications**

This section describes the DC and AC electrical specifications for the PIC.

# **2.15.1 PIC DC Electrical Characteristics**

This table provides the DC electrical characteristics for the PIC interface when operating at  $CV<sub>DD</sub>/OV<sub>DD</sub>/BV<sub>DD</sub>/X1V<sub>DD</sub>/X2V<sub>DD</sub> = 3.3 V.$ 

## **Table 60. PIC DC Electrical Characteristics (3.3 V)**

For recommended operating conditions, see [Table 3.](#page-48-0)



## **Table 60. PIC DC Electrical Characteristics (3.3 V) (continued)**

For recommended operating conditions, see Table 3.



#### **Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max  $CV_{IN}/OV_{IN}/BV_{IN}/X1V_{IN}/X2V_{IN}$  values found in [Table 3.](#page-48-0)

2. Note that the symbol  $CV_{IN}/OV_{IN}/BV_{IN}/X1V_{IN}/X2V_{IN}$  represents the input voltage of the supply. See [Table 3](#page-48-0).

This table provides the DC electrical characteristics for the PIC interface when operating at  $LV_{DD}/OV_{DD}/BV_{DD}/CV_{DD} = 2.5$  V.

#### **Table 61. PIC DC Electrical Characteristics (2.5 V)**

For recommended operating conditions, see [Table 3](#page-48-0).



**Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max  $CV_{IN}/OV_{IN}/BV1V_{IN}/X2V_{IN}$  values found in [Table 3](#page-48-0).

2. Note that the symbol  $CV_{IN}/OV_{IN}/BV_{IN}/X1V_{IN}/X2V_{IN}$  represents the input voltage of the supply. See [Table 3.](#page-48-0)

This table provides the DC electrical characteristics for the PIC interface when operating at  $LV_{DD}/OV_{DD}/BV_{DD}/CV_{DD} = 1.8$  V.

**Table 62. PIC DC Electrical Characteristics (1.8 V)**

For recommended operating conditions, see [Table 3](#page-48-0).



## **Table 62. PIC DC Electrical Characteristics (1.8 V) (continued)**

For recommended operating conditions, see Table 3.



#### **Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max  $CV_{IN}/OV_{IN}/BV_{IN}/X1V_{IN}/X2V_{IN}$  values found in [Table 3](#page-48-0).

2. Note that the symbol  $CV_{IN}/OV_{IN}/BV_{IN}/X1V_{IN}/X2V_{IN}$  represents the input voltage of the supply. See [Table 3.](#page-48-0)

# **2.15.2 PIC AC Timing Specifications**

This table provides the PIC input and output AC timing specifications.

### **Table 63. PIC Input AC Timing Specifications**

For recommended operating conditions, see [Table 3](#page-48-0)



**Note:**

1. PIC inputs and outputs are asynchronous to any visible clock. PIC outputs should be synchronized before use by any external synchronous logic. PIC inputs are required to be valid for at least  $t_{PIWID}$  ns to ensure proper operation when working in edge-triggered mode.

# **2.16 JTAG**

This section describes the AC electrical specifications for the IEEE Std 1149.1™ (JTAG) interface. This section applies to both the Power Architecture and DSP JTAG ports. The BSC9131 has multiple JTAG topology; see [Section 3.9, "JTAG Configuration](#page-119-0)  [Signals](#page-119-0)," for details.

# **2.16.1 JTAG DC Electrical Characteristics**

This table provides the JTAG DC electrical characteristics.

### **Table 64. JTAG DC Electrical Characteristics**

For recommended operating conditions, see [Table 3.](#page-48-0)



**Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max OV<sub>IN</sub> values found in [Table 3](#page-48-0)

2. Note that the symbol OV<sub>IN</sub> represents the input voltage of the supply. It is referenced in [Table 3.](#page-48-0)

# **2.16.2 JTAG AC Timing Specifications**

This table provides the JTAG AC timing specifications as defined in [Figure 30](#page-91-0) through [Figure 33](#page-92-0).

## **Table 65. JTAG AC Timing Specifications**

For recommended operating conditions see [Table 3.](#page-48-0)



### **Table 65. JTAG AC Timing Specifications (continued)**

For recommended operating conditions see Table 3.



**Note:**

- 1. The symbols used for timing specifications follow the pattern t<sub>(first two letters of functional block)(signal)(state)(reference)(state) for inputs</sub> and t<sub>(first two letters of functional block)(reference)(state)(signal)(state)</sub> for outputs. For example, t<sub>JTDVKH</sub> symbolizes JTAG device timing (JT) with respect to the time data input signals (D) reaching the valid state (V) relative to the t<sub>JTG</sub> clock reference (K) going to the high (H) state or setup time. Also, t<sub>JTDXKH</sub> symbolizes JTAG timing (JT) with respect to the time data input signals (D) reaching the invalid state (X) relative to the  $t_{JTG}$  clock reference (K) going to the high (H) state. Note that in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
- 2. TRST is an asynchronous level sensitive signal. The setup time is for test purposes only.
- 3. All outputs are measured from the midpoint voltage of the falling/rising edge of  $t_{TCLK}$  to the midpoint of the signal in question. The output timings are measured at the pins. All output timings assume a purely resistive 50-Ω load. Time-of-flight delays must be added for trace lengths, vias, and connectors in the system.

This figure provides the AC test load for TDO and the boundary-scan outputs.



**Figure 30. AC Test Load for the JTAG Interface**

<span id="page-91-0"></span>This figure provides the JTAG clock input timing diagram.



**Figure 31. JTAG Clock Input Timing Diagram**

This figure provides the TRST\_B timing diagram.



**Figure 32. TRST\_B Timing Diagram**

This figure provides the boundary-scan timing diagram.



VM = Midpoint Voltage (OV<sub>DD</sub>/2)

**Figure 33. Boundary-Scan Timing Diagram**

# <span id="page-92-0"></span>**2.17 I2C**

This section describes the DC and AC electrical characteristics for the two  $I^2C$  interfaces. The input voltage for  $I^2C1$  is provided by a  $\text{OV}_{\text{DD}}$  (3.3 V) power supply, while the input voltage for I<sup>2</sup>C2 is provided by a CV<sub>DD</sub> (3.3 V/1.8 V) power supply.

# **2.17.1 I2C DC Electrical Characteristics**

This table provides the DC electrical characteristics for the  $I<sup>2</sup>C$  interfaces operating from a 3.3 power supply.

Table 66.  $I^2C$  DC Electrical Characteristics ( $CV_{DD} = 3.3 V$ )

<span id="page-92-1"></span>For recommended operating conditions, see [Table 3](#page-48-0)



**Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max CV<sub>IN</sub> values found in [Table 3](#page-48-0).

2. Output voltage (open drain or open collector) condition = 3 mA sink current.

3. See the BSC9131 QorIQ Qonverge Multicore Baseband Processor Reference Manual for information on the digital filter used.

4. I/O pins obstruct the SDA and SCL lines if  $\textsf{OV}_{\textsf{DD}}$  is switched off.

This table provides the DC timing parameters for the  $I<sup>2</sup>C$  interface operating from a 1.8 V power supply.

# Table 67. I<sup>2</sup>C DC Electrical Characteristics (CV<sub>DD</sub> = 1.8 V)

For recommended operating conditions, see [Table 3](#page-48-0).



**Note:**

1. Note that the min V<sub>IL</sub> and max V<sub>IH</sub> values are based on the respective min and max CV<sub>IN</sub> values found in [Figure 3](#page-48-0).

2. Note that the symbol CV<sub>IN</sub> represents the input voltage of the supply. It is referenced in [Figure 3](#page-48-0).

# **2.17.2 I2C AC Electrical Specifications**

This table provides the AC timing parameters for the  $I<sup>2</sup>C$  interfaces.

## **Table 68. I2C AC Electrical Specifications**

For recommended operating conditions see [Table 3.](#page-48-0) All values refer to  $V_{H}$  (min) and  $V_{IL}$  (max) levels (see [Table 66](#page-92-1))



## **Table 68. I2C AC Electrical Specifications (continued)**

For recommended operating conditions see Table 3. All values refer to  $V_{\text{IH}}$  (min) and  $V_{\text{IL}}$  (max) levels (see Table 66)



#### **Note:**

- 1. The symbols used for timing specifications herein follow the pattern t<sub>(first two letters of functional block)(signal)(state)(reference)(state) for</sub> inputs and t<sub>(first two letters of functional block)(reference)(state)(signal)(state)</sub> for outputs. For example, t<sub>12DVKH</sub> symbolizes I<sup>2</sup>C timing (I2) with respect to the time data input signals (D) reaching the valid state (V) relative to the t<sub>I2C</sub> clock reference (K) going to the high (H) state or setup time. Also,  $t_{12SXKL}$  symbolizes  $I^2C$  timing (I2) for the time that the data with respect to the START condition (S) went invalid (X) relative to the t<sub>I2C</sub> clock reference (K) going to the low (L) state or hold time. Also, t<sub>I2PVKH</sub> symbolizes I<sup>2</sup>C timing (I2) for the time that the data with respect to the STOP condition (P) reaches the valid state (V) relative to the  $t<sub>12C</sub>$  clock reference (K) going to the high (H) state or setup time.
- 2. The requirements for I<sup>2</sup>C frequency calculation must be followed. See Freescale application note AN2919, "Determining the I2C Frequency Divider Ratio for SCL."
- 3. As a transmitter, the device provides a delay time of at least 300 ns for the SDA signal (referred to as the  $V<sub>Hmin</sub>$  of the SCL signal) to bridge the undefined region of the falling edge of SCL to avoid unintended generation of a START or STOP condition. When the device acts as the  $I^2C$  bus master while transmitting, it drives both SCL and SDA. As long as the load on SCL and SDA are balanced, the device does not generate an unintended START or STOP condition. Therefore, the 300 ns SDA output delay time is not a concern. If under some rare condition, the 300 ns SDA output delay time is required for the device as transmitter, application note AN2919 referred to in note 4 below is recommended.
- 4. The maximum t<sub>I2OVKL</sub> has only to be met if the device does not stretch the LOW period (t<sub>I2CL</sub>) of the SCL signal.

This figure provides the AC test load for the  $I<sup>2</sup>C$ .



**Figure 34. I2C AC Test Load**

This figure shows the AC timing diagram for the  $I<sup>2</sup>C$  bus.



**Figure 35. I2C Bus AC Timing Diagram**

# **2.18 GPIO**

This section describes the DC and AC electrical specifications for the GPIO interface.

# **2.18.1 GPIO DC Electrical Characteristics**

This table provides the DC electrical characteristics for the GPIO interface when operating from 3.3-V supply.

### **Table 69. GPIO DC Electrical Characteristics (3.3 V)**

For recommended operating conditions, see [Table 3](#page-48-0)



#### **Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the min and max BV<sub>IN</sub> respective values found in [Table 3](#page-48-0).

2. Note that the symbol  $BV_{\text{IN}}$  represents the input voltage of the supply. It is referenced in [Table 3.](#page-48-0)

This table provides the DC electrical characteristics for the GPIO interface when operating from 2.5-V supply.

#### **Table 70. GPIO DC Electrical Characteristics (2.5 V)**

For recommended operating conditions, see [Table 3.](#page-48-0)



#### **Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the min and max BV<sub>IN</sub> respective values found in [Table 3](#page-48-0).

2. Note that the symbol  $BV_{\text{IN}}$  represents the input voltage of the supply. It is referenced in [Table 3.](#page-48-0)

This table provides the DC electrical characteristics for the GPIO interface when operating from 1.8-V supply.

#### **Table 71. GPIO DC Electrical Characteristics (1.8 V)**

For recommended operating conditions, see [Table 3.](#page-48-0)



## **Table 71. GPIO DC Electrical Characteristics (1.8 V) (continued)**

For recommended operating conditions, see Table 3.



**Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the min and max BV<sub>IN</sub> respective values found in [Table 3.](#page-48-0)

2. Note that the symbol  $BV_{\text{IN}}$  represents the input voltage of the supply. It is referenced in [Table 3](#page-48-0).

# **2.18.2 GPIO AC Timing Specifications**

This table provides the GPIO input and output AC timing specifications.

### **Table 72. GPIO Input AC Timing Specifications**

For recommended operating conditions, see [Table 3](#page-48-0)



#### **Note:**

1. GPIO inputs and outputs are asynchronous to any visible clock. GPIO outputs should be synchronized before use by any external synchronous logic. GPIO inputs are required to be valid for at least  $t_{PIW|D}$  to ensure proper operation.

This figure provides the AC test load for the GPIO.



**Figure 36. GPIO AC Test Load**

# **2.19 TDM**

This section describes the DC and AC electrical specifications for the TDM.

# **2.19.1 TDM DC Electrical Characteristics**

This table provides the DC electrical characteristics for the TDM interface when operating at 3.3 V.

## Table 73. TDM DC Electrical Characteristics (BV<sub>DD</sub>/X2V<sub>DD</sub> = 3.3 V)

For recommended operating conditions, see [Table 3](#page-48-0).



## Table 73. TDM DC Electrical Characteristics (BV<sub>DD</sub>/X2V<sub>DD</sub> = 3.3 V) (continued)

For recommended operating conditions, see Table 3.



**Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the min and max  $BV_{IN}/X2V_{IN}$  respective values found in [Table 3](#page-48-0) 2. Note that the symbol  $BV_{\text{IN}}/X2V_{\text{IN}}$  represents the input voltage of the supply. It is referenced in [Table 3](#page-48-0)

<span id="page-97-0"></span>[Table 74](#page-97-0) provides the DC electrical characteristics for the TDM interface when operating at 2.5 V.

### **Table 74. TDM DC Electrical Characteristics (BV<sub>DD</sub> = 2.5 V)**

For recommended operating conditions, see [Table 3.](#page-48-0)



**Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max BV<sub>IN</sub> values found in [Table 3](#page-48-0).

2. Note that the symbol  $BV_{IN}$  represents the input voltage of the supply. It is referenced in [Table 3.](#page-48-0)

This table provides the DC electrical characteristics for the TDM interface when operating at 1.8 V.

## Table 75. TDM DC Electrical Characteristics (BV<sub>DD</sub>/X2V<sub>DD</sub> = 1.8 V)

For recommended operating conditions, see [Table 3.](#page-48-0)



**Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the min and max BV<sub>IN</sub>/X2V<sub>IN</sub> respective values found in [Table 3](#page-48-0)

2. Note that the symbol  $BV_{IN}/X2V_{IN}$  represents the input voltage of the supply. It is referenced in [Table 3](#page-48-0)

# **2.19.2 TDM AC Electrical Characteristics**

This table provides the input and output AC timing specifications for the TDM interface.

## **Table 76. TDM AC Timing Specifications for 62.5 MHz<sup>1</sup>**



<b>Parameter</b>	Symbol <sup>2</sup>	Min	Max	Unit	<b>Note</b>
TDMxRCK/TDMxTCK high pulse width	<sup>t</sup> DM_HIGH	7.0		ns	3
TDMxRCK/TDMxTCK low pulse width	t <sub>DM_LOW</sub>	7.0		ns	3
TDM all input setup time	t <sub>DMIVKH</sub>	3.6		ns	4, 5
TDMxRD input hold time	<sup>I</sup> DMRDIXKH	1.9		ns	4, 8
TDMxTFS/TDMxRFS input hold time	<sup>t</sup> DMFSIXKH	1.9		ns	5
TDMxTCK high to TDMxTD output active	<sup>t</sup> DM_OUTAC	2.5		ns	7
TDMxTCK high to TDMxTD output valid	<sup>t</sup> DMTKHOV		9.8	ns	7, 9
TDMxTD hold time	<sup>t</sup> DMTKHOX	2.5		ns	7
TDMxTCK high to TDMxTD output high impedance	<sup>t</sup> DM_OUTHI		9.8	ns	$\overline{7}$
TDMxTFS/TDMxRFS output valid	<sup>t</sup> DMFSKHOV		9.25	ns	6
TDMxTFS/TDMxRFS output hold time	<sup>t</sup> DMFSKHOX	2.0		ns	6

**Table 76. TDM AC Timing Specifications for 62.5 MHz<sup>1</sup> (continued)**

**Note:** Output values are based on 30 pF capacitive load.

**Note:** Inputs are referenced to the sampling that the TDM is programmed to use. Outputs are referenced to the programming edge they are programmed to use. Use of the rising edge or falling edge as a reference is programmable.  $t_{DMxTCK}$  and  $t_{DMxBCK}$  are shown using the rising edge.

1. All values are based on a maximum TDM interface frequency of 62.5 MHz.

2. The symbols used for timing specifications follow the pattern t<sub>(first two letters of functional block)(signal)(state)(reference)(state) for inputs</sub> and t<sub>(first two letters of functional block)(reference)(state)(signal)(state) for outputs. For example, t<sub>HIKHOX</sub> symbolizes the output internal</sub> timing (HI) for the time t<sub>serial</sub> memory clock reference (K) goes from the high state (H) until outputs (O) are invalid (X).

- 3. Relevant for all pins that function as TDM RX/TX clock—pins may be TDM\_RCK and TDM\_TCK, pending TDM port configuration.
- 4. Relevant for all pins that function as TDM receive data—pins may be TDM\_RCK, TDM\_RSN, TDM\_RDT, TDM\_TDT, pending TDM port configuration.
- 5. Relevant for all pins that function as TDM input frame sync (TX/RX)—pins may be TDM\_TSN, TDM\_RSN, pending TDM port configuration.
- 6. Relevant for all pins that function as TDM output frame sync (TX/RX)—pins may be TDM\_TSN, TDM\_RSN, pending TDM port configuration.
- 7. Relevant for all pins that function as TDM transmit data—pins may be TDM\_RCK, TDM\_RSN, TDM\_RDT, TDM\_TDT, pending TDM port configuration.
- 8. Applies to any TDM pin that functions as Rx data (including TDMxTD and others).
- 9. Represents the time from the positive clock edge to the valid data on the Tx data like; it applies to any TDM pin that functions as Tx data (including TDMxRD and others).

This figure shows the TDM receive signal timing.



This figure shows the TDM transmit signal timing.





This figure provides the AC test load for the TDM.



**Figure 39. TDM AC Test Load**

# **2.20 Radio Frequency (RF) Interface**

# **2.20.1 RF Parallel Interface**

There are two RF interfaces—parallel and MaxPHY serial interfaces.

# **2.20.1.1 RF Parallel Interface DC Electrical Characteristics (eSPI2)**

# **2.20.1.1.1 RF Parallel Interface DC Data Path**

<span id="page-100-0"></span>[Table 77](#page-100-0) provides the DC electrical characteristics for the RF parallel interface when operating at 3.3 V.

### Table 77. RF Parallel Interface DC Electrical Characteristics (X1V<sub>DD</sub>, X2V<sub>DD</sub> = 3.3 V)

For recommended operating conditions, see [Table 3.](#page-48-0)



**Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max  $X1V_{IN}/X2V_{IN}$  values found in [Table 3](#page-48-0).

2. Note that the symbol  $X1V_{IN}/X2V_{IN}$  represent the input voltage of the power supplies. It is referenced in [Table 3](#page-48-0).

<span id="page-100-1"></span>[Table 78](#page-100-1) provides the DC electrical characteristics for the RF interface when operating at 1.8 V.

## **Table 78. RF Parallel Interface DC Electrical Characteristics (X1V<sub>DD</sub>, X2V<sub>DD</sub> = 1.8 V)**

For recommended operating conditions, see [Table 3.](#page-48-0)



**Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max  $X1V_{IN}/X2V_{IN}$  values found in [Table 3](#page-48-0).

2. Note that the symbol  $X1V_{\text{IN}}/X2V_{\text{IN}}$  represents the input voltage of the supply. It is referenced in [Table 3](#page-48-0).

# **2.20.1.1.2 RF Parallel Interface DC Control Plane**

See [Table 33](#page-67-0) in [Section 2.9.1, "eSPI1 DC Electrical Characteristics](#page-67-1)," for the DC specs for eSPI2, powered by  $X2V_{DD} = 1.8$  V.

# **2.20.1.2 RF Parallel Interface AC Electrical Characteristics (eSPI2)**

# **2.20.1.2.1 RF Parallel AC Data Interface**

<span id="page-101-1"></span>[Table 79](#page-101-1) provides the timing specifications for the RF parallel interface.

# **Table 79. RF Parallel Interface Timing Specification (3.3 V, 1.8 V)[1,](#page-101-0)2**



**Note:**

<span id="page-101-0"></span> $1$  The max trace delay of MCLK from the external RFIC to the BSC9131 BBIC and FCK/TXNRX/ENABLE from BBIC to RFIC = 1 ns each.

<sup>2</sup> The max allowable trace skew between MCLK/FCLK and the respective data/control is 70 ps.

 $3\,$  1.37 ns includes 70 ps trace skew.





## **2.20.1.2.2 RF Parallel Interface AC Control Plane**

## **Table 80. RF Parallel Control Plane Interface AC Timing Specification**



**Note:** RF parallel control plane is SPI2; RF serial control plane is SPI3 and SPI4.



t<sub>BD</sub>: Board delay from the BSC9131 BBIC to the external RFIC or  $\:$  **Data timing at RF parallel interface:** back  $t_{CO}$ : Delay in RFIC from input of SPICLK to output valid data Max permissible board skew: 100 ps Proposed frequency of SPICLK: 30 MHz Input data setup requirement: 1 ns Input data hold requirement: 0 ns  $t_{CO}$ : 4.5 ns–6.5 ns (6.5 ns is critical, which defines the max frequency)

#### **Figure 41. RF Parallel Control Plane Interface AC Timing Diagram**

# **2.20.2 RF Serial (MaxPHY) Interface**

# **2.20.2.1 RF Serial (MaxPHY) Interface DC Electrical Characteristics (eSPI3, eSPI4)**

## **2.20.2.1.1 RF Serial (MaxPHY) Interface DC Data Path**

### **Table 81. RF Serial Interface DC Electrical Characteristics**

For recommended operating conditions, see [Table 3.](#page-48-0)



**Note:**

1. Used to define a differential signal slew rate.

2. These values are not defined. However, each signal must be within the respective limites for inputs as well as the limitations for overshoot and undershoot (see [Table 82](#page-104-0) for specifications).

<span id="page-104-0"></span>[Table 82](#page-104-0) provides the AC overshoot/undershoot specifications; see [Figure 42](#page-104-1) for the areas referenced.

<b>Parameter</b>	Maxim 153.6 MHz
Maximum peak amplitude allowed for overshoot area	0.4
Maximum peak amplitude allowed for undershoot area	0.4
Maximum overshoot area above RVDD	0.25
Maximum overshoot area below GND	0.25

**Table 82. AC Overshoot/Undershoot Specification for Clock and Data**



**Figure 42. RF Serial Interface AC Overshoot/Undershoot Diagram**

## <span id="page-104-1"></span>**2.20.2.1.2 RF Serial (MaxPHY) Interface DC Control Plane**

See [Table 33](#page-67-0) in [Section 2.9.1, "eSPI1 DC Electrical Characteristics](#page-67-1)," for the DC specs for eSPI3 and eSPI4, powered by  $X1V_{DD} = 1.8 V$ .

# **2.20.2.2 RF Serial (MaxPHY) Interface AC Electrical Characteristics (eSPI3, eSPI4)**

## **2.20.2.2.1 RF Serial (MaxPHY) AC Data Interface**

<span id="page-104-2"></span>[Table 83](#page-104-2) provides the timing specifications for the RF parallel interface.

### **Table 83. RF Serial Interface Timing Specification**



### **Note:**

<span id="page-104-3"></span> $1$  The maximum trace skew between TXLCK and data is estimated <50 ps.

<sup>2</sup> Assuming 50 ps worst trace skew.



**Figure 43. RF Serial Interface AC Timing Diagram**

# **2.20.2.2.2 RF Serial (MaxPHY) Interface AC Control Plane**





**Note:**

<sup>1</sup> Wrt 30 MHz SPICLK

<sup>2</sup> Wrt 25 MHz SPICLK



Proposed max frequency: 25 MHz Max board skey permissible: 100 ps Input data hold requirement: 6 ns  $t_{\text{CO}}$ : 12.5 ns



# **2.20.2.2.3 RF Serial (MaxPHY) Jitter and Skew Specfications**



## **Table 85. RF Serial (MaxPHY) Jitter and Skew Specifications**

# **2.20.3 Pulse-Width Modulator (PWM)**

There are two pulse-width modulators (PWM). Both PWMs are connected at two different pins. The output of PWM is pulse-width modulated signal (PWMO) available at external output pin.

# **2.20.3.1 PWM Timing**

[Figure 45](#page-107-0) shows the timing diagram of PWM.



**Figure 45. PWM Timing Diagram**

<span id="page-107-1"></span><span id="page-107-0"></span>[Table 86](#page-107-1) lists the PWM output timing characteristics.

**Table 86. PWM Output Timing Parameter**

Ref No.	<b>Parameter</b>	<b>Minimum</b>	<b>Maximum</b>	Unit
	Output pulse width	(1/f <sub>platform_clk</sub> )		ns
2a	Output rise time	TBD	TBD	ns
2b	Output fall time	TBD	TBD	ns

# **2.21 Universal Subscriber Identity Module (USIM)**

The USIM module interface consist of a total of five pins. Only "Internal One Wire" interface mode is supported. In this mode, the Rx input of the USIM IP is connected to the TX output of the USIM, which is internal to the device. Only one bidirectional signal (Rx/Tx) is routed to the device pin, which is connected to the external SIM card.

The interface is meant to be used with synchronous SIM cards. This means that the SIM module provides a clock for the SIM card to use. The frequency of this clock is normally 372 times the data rate on the Rx/Tx pins; however, the SIM module can work with CLK equal to 16 times the data rate on Rx/Tx pins.

There is no timing relationship between the clock and the data. The clock that the SIM module provides to the SIM card will be used by the SIM card to recover the clock from the data much like a standard UART. All five pins of SIM module are asynchronous to each other.

There are no required timing relationships between the pads in normal mode, The SIM card is initiated by the interface device, whereupon the SIM card will send a response with an Answer to Reset. Although the SIM interface has no specific requirement, the ISO-7816 specifies reset and power down sequences. For detailed information, see ISO-7816.

The USIM interface pins are available at two locations. At one location, it is multiplexed with eSDHC and TDM functionality and is powered by the BVDD power supply (3.3V/2.5V/1.8V). At the other location, it is multiplexed with eSPI and UART functionality and is powered by CVDD power supply (3.3V/1.8V).
**Electrical Characteristics**

# **2.21.1 USIM DC Electrical Characteristics**

This table provides the DC electrical characteristics for the USIM interface.

### **Table 87. USIM Interface DC Electrical Characteristics**

At recommended operating conditions with  $BV_{DD} = 3.3 V/2.5 V/1.8 V$ .



#### **Note:**

1. Note that the min V<sub>IL</sub>and max V<sub>IH</sub> values are based on the respective min and max BV<sub>IN</sub> values found in [Figure 3](#page-48-0).

2. Open drain mode for SIM cards only.

# **2.21.2 USIM General Timing Requirements**

<span id="page-108-0"></span>The timing requirements for the USIM are found in [Table 88](#page-108-0).

## **Table 88. USIM Timing Specification, High Drive Strength**



**Note:**

<sup>1</sup> 50% duty cycle clock

- <sup>2</sup> With  $C = 50$  pF
- $3$  With CIN = 30 pF, COUT = 30 pF
- <sup>4</sup> With  $C_{1N}$  = 30 pF



**Figure 46. USIM Clock Timing Diagram**

#### **Electrical Characteristics**

## **2.21.3 USIM External Pull Up/Pull Down Resistor Requirements**

External off-chip pull up resistor of 20 K $\Omega$  is required on the SIM\_TRXD pin.

External off-chip pull down resistors are required on the SIM\_PD, SIM\_SVEN, SIM\_RST pins.

## **2.21.4 USIM Reset Sequence**

## **2.21.4.1 SIM Cards With Internal Reset**

The sequence of reset for this kind of SIM cards is as follows (see [Figure 47](#page-109-0)):

- After power up, the clock signal is enabled on SIM\_CLK (time T0).
- After 200 clock cycles, Rx must be high.
- The card must send a response on Rx acknowledging the reset between 400 and 40000 clock cycles after T0.



**Figure 47. Internal-Reset Card Reset Sequence**



<span id="page-109-0"></span>

## **2.21.4.2 SIM Cards With Active-Low Reset**

The sequence of reset for this kind of card is as follows (see [Figure 48\)](#page-110-0):

- After powering up, the clock signal is enabled on SIM\_CLK (time T0).
- After 200 clock cycles, SIM\_TRXD must be high.
- SIM\_RST must remain Low for at least 40000 clock cycles after T0 (no response is to be received on Rx during those 40000 clock cycles).
- SIM\_RST is set High (time T1).
- SIM\_RST must remain High for at least 40000 clock cycles after T1 and a response must be received on SIM\_TRXD between 400 and 40000 clock cycles after T1.



### **Figure 48. Active-Low Reset Card Reset Sequence**

#### **Table 90. Parameters of Reset Sequence For Active-Low Reset Card**

<span id="page-110-0"></span>

## **2.21.4.3 USIM Power Down Sequence**

Power down sequence for SIM interface is as follows:

- SIM\_PD port detects the removal of the SIM card
- SIM\_RST goes low
- SIM\_CLK goes low
- SIM\_TRXD goes low
- SIM\_SVEN goes low

#### **Electrical Characteristics**

Each of these steps is done in one CKIL period (typically 32 KHz). Power down is initiated by detection of a SIM card removal or is launched by the processor. See [Figure 49](#page-111-0) and [Table 91](#page-111-1) for the timing requirements for this sequence, with  $F_{CKIL} = CKIL$ frequency value.



**Figure 49. SmartCard Interface Power Down AC Timing**



<span id="page-111-1"></span><span id="page-111-0"></span>

# **2.22 Timers and Timers\_32b AC Timing Specifications**

This table lists the timer input AC timing specifications.

### **Table 92. Timers Input AC Timing Specifications**

For recommended operating conditions, see [Table 3](#page-48-0).



**Note:**

1. The maximum allowed frequency of timer outputs is 125 MHz. Configure the timer modules appropriately.

2. Timer inputs and outputs are asynchronous to any visible clock. Timer outputs should be synchronized before use by any external synchronous logic. Timer inputs are required to be valid for at least  $t_{T|W|D}$  ns to ensure proper operation.

This figure shows the AC test load for the timers.



**Figure 50. Timer AC Test Load**

# **3 Hardware Design Considerations**

This section discusses the hardware design considerations.

# **3.1 Power Architecture System Clocking**

This section describes the PLL configuration for the Power Architecture side of the device. Note that the platform clock is identical to the internal core complex bus (CCB) clock.

This device includes 3 PLLs, as follows:

- The platform PLL generates the platform clock from the externally supplied SYSCLK input. The frequency ratio between the platform and SYSCLK is selected using the platform PLL ratio configuration bits as described in [Section 3.1.2, "Power Architecture Platform to SYSCLK PLL Ratio.](#page-113-0)"
- The e500 core PLL generates the core clock from the platform clock. The frequency ratio between the e500 core clock and the platform clock is selected using the e500 PLL ratio configuration bits as described in [Section 3.1.3, "e500 Core](#page-114-0)  [to Platform Clock PLL Ratio](#page-114-0)."
- The DDR PLL generates the clocking for the DDR SDRAM controller. The frequency ratio between DDR clock and platform clock is selected using the DDR PLL ratio configuration bits as described in section [Section 3.1.4, "Power](#page-114-1)  [Architecture DDR/DDRCLK PLL Ratio.](#page-114-1)"
- The MAPLE eTVPE clock is sourced from the DDR PLL and has a maximum frequency of 800 MHz.

## **3.1.1 Power Architecture Clock Ranges**

<span id="page-112-0"></span>[Table 93](#page-112-0) provides the clocking specifications for the processor core and platform.

#### **Table 93. Power Architecture Processor Clocking Specifications**





### **Table 93. Power Architecture Processor Clocking Specifications (continued)**

**Note:**

- 1. **Caution:** The Power Architecture platform clock to SYSCLK ratio and e500 core to platform clock ratio settings must be chosen such that the resulting SYSCLK frequency, e500 (core) frequency, and platform clock frequency do not exceed their respective maximum or minimum operating frequencies. See [Section 3.1.2, "Power Architecture Platform to SYSCLK PLL](#page-113-0)  [Ratio,](#page-113-0)" and [Section 3.1.3, "e500 Core to Platform Clock PLL Ratio](#page-114-0)" and [Section 3.1.4, "Power Architecture DDR/DDRCLK PLL](#page-114-1)  [Ratio,](#page-114-1)" for ratio settings.
- 2. The minimum e500 core frequency is based on the minimum platform clock frequency of 267 MHz.
- 3. The reset config signal cfg\_core\_speed must be pulled low if the core frequency is 500 MHz or below.
- 4. These values are preliminary and subject to change.
- 5. The reset config signal cfg\_plat\_speed must be pulled low if the CCB bus frequency is lower than 320 MHz.

The DDR memory controller can run in asynchronous mode.

<span id="page-113-1"></span>[Table 94](#page-113-1) provides the clocking specifications for the memory bus.

#### **Table 94. Power Architecture Memory Bus Clocking Specifications**



**Note:**

- 1. **Caution:** The platform clock to SYSCLK ratio and e500 core to platform clock ratio settings must be chosen such that the resulting SYSCLK frequency, e500 (core) frequency, and platform frequency do not exceed their respective maximum or minimum operating frequencies. See [Section 3.1.2, "Power Architecture Platform to SYSCLK PLL Ratio,](#page-113-0)" and [Section 3.1.3,](#page-114-0)  ["e500 Core to Platform Clock PLL Ratio,](#page-114-0)" and [Section 3.1.4, "Power Architecture DDR/DDRCLK PLL Ratio](#page-114-1)," for ratio settings.
- 2. The memory bus clock refers to the memory controllers' Dn\_MCK[0:5] and Dn\_MCK[0:5]\_B output clocks, running at half of the DDR data rate.
- 3. In asynchronous mode, the memory bus clock speed is dictated by its own PLL. See [Section 3.1.4, "Power Architecture](#page-114-1)  [DDR/DDRCLK PLL Ratio](#page-114-1)." The memory bus clock speed must be less than or equal to the platform clock rate, which in turn must be less than the DDR data rate.

As a general guideline, the following procedures can be used for selecting the DDR data rate or platform frequency:

- 1. Start with the processor core frequency selection.
- 2. Once the processor core frequency is determined, select the platform frequency from the options listed in [Table 96](#page-114-2) and [Table 100.](#page-115-0)
- 3. Check the platform to SYSCLK ratio to verify a valid ratio can be chosen from [Table 98.](#page-115-1)
- 4. Please note that the DDR data rate must be greater than the platform frequency. In other words, running DDR data rate lower than the platform frequency is not supported.
- 5. Verify all clock ratios to ensure that there is no violation to any clock and/or ratio specification.

# <span id="page-113-0"></span>**3.1.2 Power Architecture Platform to SYSCLK PLL Ratio**

The clock that drives the internal CCB bus is called the platform clock. The frequency of the platform clock is set using the following reset signals, as shown in [Table 95:](#page-114-3)

SYSCLK input signal

• Binary value on IFC\_AD[0:2] at power up

These signals must be pulled to the desired values.

<span id="page-114-3"></span>In asynchronous mode, the memory bus clock frequency is decoupled from the platform bus frequency.

Binary Value of IFC_AD[0:2] Signals	<b>Platform: SYSCLK Ratio</b>
000	4:1
001	5:1
010	6:1
All Others	Reserved

**Table 95. Power Architecture Platform/SYSCLK Clock Ratios**

## <span id="page-114-0"></span>**3.1.3 e500 Core to Platform Clock PLL Ratio**

<span id="page-114-2"></span>The clock ratio between the e500 core and the platform clock is determined by the binary value of IFC\_AD[3:5] signals at power up. [Table 96](#page-114-2) describes the supported ratios. There are no default values for these PLL ratios; these signals must be pulled to the desired values. Note that IFC\_AD[6] must be pulled low if the core frequency is 500 MHz or below.

<b>Binary Value of</b> IFC_AD[3:5]Signals	e500 Core: Platform <b>Ratio</b>
010	1:1
011	1.5:1
100	2:1
101	2.5:1
110	3:1
All Others	Reserved

**Table 96. e500 Core to Platform Clock Ratios**

## <span id="page-114-1"></span>**3.1.4 Power Architecture DDR/DDRCLK PLL Ratio**

[Table 97](#page-114-4) describes the clock ratio between the DDR memory controller complex and the DDR PLL reference clock, DDRCLK, which is not the memory bus clock. The DDR memory controller complex clock frequency is equal to the DDR data rate.

<span id="page-114-4"></span>The DDR PLL rate to DDRCLK ratios listed in [Table 97](#page-114-4) reflects the DDR data rate to DDRCLK ratio, since the DDR PLL rate in asynchronous mode means the DDR data rate resulting from DDR PLL output. This ratio is determined by the binary value of the IFC\_AD[7].

Binary Value of {IFC_AD[7], IFC_ADDR[22]} Signal	<b>DDR:DDRCLK Ratio</b>
00	8:1
่ 1	10:1
10	12:1
	Reserved

**Table 97. Power Architecture DDR Clock Ratio**

# **3.1.5 Power Architecture SYSCLK and Platform Frequency Options**

<span id="page-115-1"></span>[Table 98](#page-115-1) shows the expected frequency options for SYSCLK and platform frequencies.

#### **Table 98. Power Architecture SYSCLK and Platform Frequency Options**



**1)** Platform frequency values are shown rounded down to the nearest whole number (decimal place accuracy removed).

# **3.2 DSP System Clocking**

This section describes the PLL configuration for the DSP side of the device. Note that the platform clock is identical to the internal core complex bus (CCB) clock.

This device has the following PLL:

• One SC3850 core PLL

## **3.2.1 DSP Clock Ranges**

<span id="page-115-2"></span>[Table 99](#page-115-2) provides the clocking specifications for the SC3850 processor core.

#### **Table 99. DSP Processor Clocking Specifications**



## **3.2.2 DSPCLKIN and SC3850 Core Frequency Options**

<span id="page-115-0"></span>[Table 100](#page-115-0) shows the expected frequency options for DSPCLKIN and SC3850 core frequencies.

### **Table 100. Options for SC3850 Core Clocking**



# **3.3 Supply Power Default Setting**

<span id="page-116-0"></span>This device is capable of supporting multiple power supply levels on its I/O supply. [Table 101](#page-116-0) through [Table 105](#page-116-1) shows the encoding used to select the voltage level for each I/O supply. When setting the VSEL signals, "1" is selected through a pull-up resistor to OVDD (as seen in [Table 1\)](#page-8-0).



## Table 101. Default Voltage Level for BV<sub>DD</sub>

## Table 102. Default Voltage Level for CV<sub>DD</sub>



### Table 103. Default Voltage Level for X1V<sub>DD</sub>



### Table 104. Default Voltage Level for X2V<sub>DD</sub>







# <span id="page-116-1"></span>**3.4 PLL Power Supply Design**

Each of the PLLs listed above is provided with power through independent power supply pins (AVDD\_PLAT, AVDD\_CORE, AVDD\_DDR, AVDD\_DSP, and AVDD\_RF respectively). The AV<sub>DD</sub> level should always be equivalent to V<sub>DDC</sub>, and these voltages must be derived directly from  $V_{DDC}$  through a low frequency filter scheme.

The recommended solution for PLL filtering is to provide independent filter circuits per PLL power supply, as illustrated in [Figure 51,](#page-117-0) one for each of the  $AV<sub>DD</sub>$  pins. By providing independent filters to each PLL the opportunity to cause noise injection from one PLL to the other is reduced.

This circuit is intended to filter noise in the PLL's resonant frequency range from a 500-kHz to 10-MHz range. It should be built with surface mount capacitors with minimum Effective Series Inductance (ESL). Consistent with the recommendations of Dr. Howard Johnson in *High Speed Digital Design: A Handbook of Black Magic* (Prentice Hall, 1993), multiple small capacitors of equal value are recommended over a single large value capacitor.

Each circuit should be placed as close as possible to the specific AV<sub>DD</sub> pin being supplied to minimize noise coupled from nearby circuits. It should be possible to route directly from the capacitors to the AV<sub>DD</sub> pin, which is on the periphery of 624 ball FCPBGA the footprint, without the inductance of vias.

[Figure 51](#page-117-0) shows the core PLL ( $AV_{DD\_CORE}$ ) power supply filter circuit.



#### **Figure 51. PLL Power Supply Filter Circuit**

<span id="page-117-0"></span>The AVDD\_RF signal provides power for the RF PLL. This PLL generates clock for communication with the MaxPHY RF interface controller. This supply should be after low pass filter from board. Filter components, a resistor and three capacitors are required on this supply. The resistor should be connected between platform 1 V and AVDD\_RF. Platform 1 V should be directly tapped from a 1 V regulator using a star connection. Place capacitors in parallel on AVDD\_RF pin, physically close to chip. See [Figure 52.](#page-117-1)





# <span id="page-117-1"></span>**3.5 Decoupling Recommendations**

Due to large address and data buses, and high operating frequencies, the device can generate transient power surges and high frequency noise in its power supply, especially while driving large capacitive loads. This noise must be prevented from reaching other components in the system, and the device itself requires a clean, tightly regulated source of power. Therefore, it is recommended that the system designer place at least one decoupling capacitor at each VDD, BVDD, CVDD, OVDD, GVDD, LVDD, RVDD, X1VDD, and X2VDD pin of the device. These decoupling capacitors should receive their power from separate VDD, BVDD, OVDD, GVDD, LVDD, RVDD, X1VDD, X2VDD, and GND power planes in the PCB, utilizing short traces to minimize inductance. Capacitors may be placed directly under the device using a standard escape pattern. Others may surround the part.

These capacitors should have a value of 0.01 or 0.1  $\mu$ F. Only ceramic SMT (surface mount technology) capacitors should be used to minimize lead inductance, preferably 0402 or 0201 sizes.

In addition, it is recommended that there be several bulk storage capacitors distributed around the PCB, feeding the  $V_{DD}$ ,  $BV_{DD}$ ,  $\rm OV_{DD}$ ,  $\rm GV_{DD}$ , and  $\rm LV_{DD}$  planes, to enable quick recharging of the smaller chip capacitors. These bulk capacitors should have a low ESR (equivalent series resistance) rating to ensure the quick response time necessary. They should also be connected to the power and ground planes through two vias to minimize inductance. Suggested bulk capacitors—100–330 µF (AVX TPS tantalum or Sanyo OSCON).

# **3.6 Pull-Up and Pull-Down Resistor Requirements**

The device requires weak pull-up resistors on open drain type pins including I<sup>2</sup>C pins (1 kΩ is recommended) and MPIC interrupt pins  $(2-10 \text{ k}\Omega)$  is recommended).

Correct operation of the JTAG interface requires configuration of a group of system control pins as demonstrated in [Figure 54](#page-120-0). Care must be taken to ensure that these pins are maintained at a valid deasserted state under normal operating conditions, because most have asynchronous behavior, and spurious assertion gives unpredictable results.

# **3.7 Output Buffer DC Impedance**

The drivers are characterized over process, voltage, and temperature. For all buses, the driver is a push-pull single-ended driver type (open drain for  $I^2C$ ).

To measure  $Z_0$  for the single-ended drivers, an external resistor is connected from the chip pad to  $\text{OV}_{DD}$  or GND. Then, the value of each resistor is varied until the pad voltage is  $\text{OV}_{DD}/2$  (see [Figure 53](#page-118-0)). The output impedance is the average of two components, the resistances of the pull-up and pull-down devices. When data is held high, SW1 is closed (SW2 is open) and  $R_p$  is trimmed until the voltage at the pad equals  $\text{OV}_{DD}/2$ .  $R_p$  then becomes the resistance of the pull-up devices.  $R_p$  and  $R_N$ are designed to be close to each other in value. Then,  $Z_0 = (R_P + R_N) \div 2$ .



<span id="page-118-0"></span>**Figure 53. Driver Impedance Measurement**

[Table 106](#page-119-0) summarizes the signal impedance targets. The driver impedances are targeted at minimum  $V_{DDC}$ , nominal  $OV_{DD}$ , 90°C.

<span id="page-119-0"></span>

Impedance	IFC, Ethernet, DUART, Control, Configuration, Power Management	<b>DDR DRAM</b>	Symbol	Unit
$R_{N}$	43 Target	20 Target	$L_0$	W
Rр	43 Target	20 Target	$\epsilon_0$	W

**Table 106. Impedance Characteristics**

**Note:** Nominal supply voltages. See [Table 2.](#page-47-0)

# **3.8 Configuration Pin Muxing**

The device provides the user with power-on configuration options which can be set through the use of external pull-up or pull-down resistors of 4.7 kΩ on certain output pins (see customer visible configuration pins). These pins are generally used as output only pins in normal operation.

While HRESET B is asserted however, these pins are treated as inputs. The value presented on these pins while HRESET B is asserted, is latched when HRESET B deasserts, at which time the input receiver is disabled and the I/O circuit takes on its normal function. Most of these sampled configuration pins are equipped with an on-chip gated resistor of approximately 20 kΩ. This value should permit the 4.7-k $\Omega$  resistor to pull the configuration pin to a valid logic low level. The pull-up resistor is enabled only during HRESET\_B (and for platform/system clocks after HRESET\_B deassertion to ensure capture of the reset value). When the input receiver is disabled the pull-up is also, thus allowing functional operation of the pin as an output with minimal signal quality or delay disruption. The default value for all configuration bits treated this way has been encoded such that a high voltage level puts the device into the default state and external resistors are needed only when non-default settings are required by the user.

Careful board layout with stubless connections to these pull-down resistors coupled with the large value of the pull-down resistor should minimize the disruption of signal quality or speed for output pins thus configured.

The platform PLL ratio and e500 PLL ratio configuration pins are not equipped with these default pull-up devices.

# **3.9 JTAG Configuration Signals**

There are two JTAG ports:

- Power Architecture JTAG (TDI, TDO, TMS, TCK, and TRST\_B)
- DSP JTAG (DSP\_TDI, DSP\_TDO, DSP\_TMS, DSP\_TCK, and DSP\_TRST\_B)

Note that the DSP JTAG is available as a muxed option on I/O pins.

The Power Architecture JTAG is the primary JTAG interface of the chip. DSP JTAG is defined as optional debug interface. As seen in [Table 107](#page-119-1), the JTAG topology is selectable by static value driven on two pins—CFG\_0\_JTAG\_MODE and CFG\_1\_JTAG\_MODE.

<span id="page-119-1"></span>

{CFG_0_JTAG_MODE, CFG_1_JTAG_MODE}	<b>Uses Power</b> <b>Architecture</b> <b>Debug Header</b>	<b>Uses DSP</b> <b>Debug Header</b>	<b>JTAG Topology</b>
00	Yes	No.	Access Power Architecture domain and DSP domain using Power Architecture JTAG port
01	Yes	No	Access DSP domain using Power Architecture JTAG port
10	Yes	No	Access Power Architecture domain using Power Architecture JTAG port

**Table 107. JTAG Topology**



## **Table 107. JTAG Topology (continued)**

**Note:** For boundary SCAN, set {CFG\_0\_JTAG\_MODE, CFG\_1\_JTAG\_MODE} = 10.

The TRST/DSP\_TRST signal is optional in the IEEE 1149.1 specification, but is provided on the device. The device requires TRST/DSP\_TRST to be asserted during reset conditions to ensure the JTAG boundary logic does not interfere with normal chip operation. While it is possible to force the TAP controller to the reset state using only the TCK and TMS signals, generally systems assert TRST/DSP\_TRST during the power-on reset flow. Simply tying TRST/DSP\_TRST to HRESET\_B is not practical because the JTAG interface is also used for accessing the common on-chip processor (COP) function.

The COP function of the processor allow a remote computer system (typically, a PC with dedicated hardware and debugging software) to access and control the internal operations of the processor. The arrangement shown in [Figure 54](#page-120-0) and [Figure 55](#page-121-0) allows the COP/ONCE port to independently assert HRESET\_B or TRST, while ensuring that the target can drive HRESET\_B as well.

The COP interface has a standard header for connection to the target system. The 16-pin PA COP connector is shown in [Figure 54.](#page-120-0)





<span id="page-120-0"></span>The ONCE interface also has a standard header for connection to the target system. The 14-pin DSP ONCE connector is shown in [Figure 55.](#page-121-0)





## <span id="page-121-0"></span>**3.9.1 Termination of Unused Signals**

If the Power Architecture JTAG or DSP JTAG interface and COP/ONCE header is not used, Freescale recommends the following connections:

- TRST\_B should be tied to HRESET\_B through a 0 k $\Omega$  isolation resistor so that it is asserted when the system reset signal (HRESET B) is asserted, ensuring that the JTAG scan chain is initialized during the power-on reset flow. Freescale recommends that the COP header be designed into the system as shown in [Figure 54.](#page-120-0) If this is not possible, the isolation resistor allows future access to TRST\_B in case a JTAG interface may need to be wired onto the system in future debug situations.
- TCK should be pulled down to GND through a 1 kΩ resistor. This prevents TCK from changing state and reading incorrect data into the device. See AN4405, "BSC9131 QorIQ Qonverge Multicore Baseband Processor Design Checklist," for more information.
- No connection is required for TDI, TDO, or TMS.

## **NOTE**

In the case where the DSP JTAG is also used (as described in [Table 107](#page-119-1)), DSP\_TRST and DSP\_TCK need to be handled in the same way as TRST and TCK are, as mentioned above.

# **3.10 Thermal**

This section describes the thermal specifications.

## **3.10.1 Thermal Characteristics**

<span id="page-121-1"></span>[Table 108](#page-121-1) provides the package thermal characteristics.

#### **Table 108. Package Thermal Resistance Characteristics**



#### **Package Information**



#### **Table 108. Package Thermal Resistance Characteristics (continued)**

**Note:**

- 1. Junction-to-Ambient Thermal Resistance determined per JEDEC JESD51-3 and JESD51-6. Thermal test board meets JEDEC specification for this package.
- 2. Junction-to-Board thermal resistance determined per JEDEC JESD51-8. Thermal test board meets JEDEC specification for the specified package.
- 3. Junction-to-Case at the top of the package determined using MIL-STD 883 Method 1012.1. The cold plate temperature is used for the case temperature. Reported value includes the thermal resistance of the interface layer.

## <span id="page-122-0"></span>**3.10.2 Temperature Diode**

The chip has a temperature diode on the microprocessor that can be used in conjunction with other system temperature monitoring devices (such as Analog Devices, ADT7461A™). These devices use the negative temperature coefficient of a diode operated at a constant current to determine the temperature of the microprocessor and its environment.

The following are the specifications of the chip's on-board temperature diode:

Operating range: 10 – 230μA

Ideality factor over  $13.5 - 220$  μA: n =  $1.007 \pm 0.008$ 

# **3.11 Security Fuse Processor**

This device implements the QorIQ platform's Trust Architecture, supporting capabilities such as secure boot. Use of the Trust Architecture features is dependent on programming fuses in the Security Fuse Processor (SFP). The details of the Trust Architecture and SFP can be found in the *BSC9131 QorIQ Qonverge Multicore Baseband Processor Reference Manual*.

In order to program SFP fuses, the user is required to supply  $1.5$  V to the POV $_{\text{DD1}}$  pin per [Section 2.2, "Power Sequencing](#page-51-0)." POV<sub>DD1</sub> should only be powered for the duration of the fuse programming cycle, with a per device limit of one fuse programming cycle. All other times POV<sub>DD1</sub> should be connected to GND. The sequencing requirements for raising and lowering  $POV<sub>DD1</sub>$  are shown in [Figure 8](#page-52-0). To ensure device reliability, fuse programming must be performed within the recommended fuse programming temperature range per [Table 3](#page-48-0).

Users not implementing the QorIQ platform's Trust Architecture features are not required to program fuses and should connect  $POV<sub>DD1</sub>$  to GND.

# **4 Package Information**

The following section describes the detailed content and mechanical description of the package.

# **4.1 Package Parameters**

The package parameters are provided in the following list. The package type is plastic ball grid array (FC-PBGA).



### **Package Information**



# **4.2 Mechanical Dimensions of the FC-PBGA**

[Figure 56](#page-124-0) shows the package and bottom surface nomenclature.



Notes:

- 1. All dimentions are in milimeters.
- 2. Dimensions and tolerancing per ASME Y14.5-1994.
- 3. Maximum ball diameter measured parallel to Datum A.
- 4. Datum A, the seating plane, is determined by the spherical crowns of the solder balls.
- <span id="page-124-0"></span>5. Parallelism measurement shall exclude any effect of mark on top surface of package.

#### **Figure 56. BSC9131 Mechanical Dimensions and Package Diagram**

#### **Ordering Information**

# <span id="page-125-1"></span>**5 Ordering Information**

The table below provides the Freescale part numbering nomenclature for the BSC9131. Note that the individual part numbers correspond to a maximum processor core frequency. For available frequencies, contact your local Freescale sales office. Each part number also contains a revision code which refers to the die mask revision number.

<span id="page-125-0"></span>

### **Table 109. Part numbering nomenclature**

# **5.1 Part Marking**

Parts are marked as the example shown in this figure.



#### FCPBGA

**Notes:** ATWLYYWW is the traceability code. CCCCC is the country code. MMMMM is the mask number. YWWLAZ is the assembly traceability code. BSC9131CSE1HHHB is the orderable part number. See [Table 109](#page-125-0) for details.

### **Figure 57. Part Marking for FCPBGA Device**

# **6 Product Documentation**

The following documents are required for a complete description of the device and are needed to design properly with the part. Some documents may require a non-disclosure agreement. Contact your local FAE for assistance.

- *BSC9131 QorIQ Qonverge Multicore Baseband Processor Reference Manual* (BSC9131RM)
- *e500 PowerPC Core Reference Manual* (E500CORERM)

# **7 Revision History**

**Table 110. Document Revision History**



#### **How to Reach Us:**

**Home Page:** freescale.com

**Web Support:** freescale.com/support Information in this document is provided solely to enable system and software implementers to use Freescale products. There are no express or implied copyright licenses granted hereunder to design or fabricate any integrated circuits based on the information in this document.

Freescale reserves the right to make changes without further notice to any products herein. Freescale makes no warranty, representation, or guarantee regarding the suitability of its products for any particular purpose, nor does Freescale assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation consequential or incidental damages. "Typical" parameters that may be provided in Freescale data sheets and/or specifications can and do vary in different applications, and actual performance may vary over time. All operating parameters, including "typicals," must be validated for each customer application by customer's technical experts. Freescale does not convey any license under its patent rights nor the rights of others. Freescale sells products pursuant to standard terms and conditions of sale, which can be found at the following address: freescale.com/SalesTermsandConditions.

Freescale, the Freescale logo, QorIQ, and StarCore are trademarks of Freescale Semiconductor, Inc. Reg., U.S. Pat. & Tm. Off. QorIQ Qonverge is a trademark of Freescale Semiconductor, Inc. All other product or service names are the property of their respective owners. The Power Architecture and Power.org word marks and the Power and Power.org logos and related marks are trademarks and service marks licensed by Power.org. © 2014 Freescale Semiconductor, Inc.

Document Number: BSC9131 Rev. 0 03/2014



